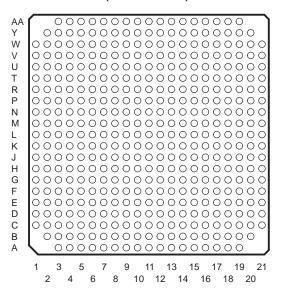
- Highest Performance Fixed-Point Digital Signal Processor (DSP) SM/SMJ320C6201B
  - 5-, 6.7-ns Instruction Cycle Time
  - 150 and 200-MHz Clock Rate
  - Eight 32-Bit Instructions/Cycle
  - 1200 and 1600 MIPS
- VelociTI™ Advanced Very Long Instruction Word (VLIW) 'C62x CPU Core
  - Eight Independent Functional Units:
    - Six ALUs (32-/40-Bit)
    - Two 16-Bit Multipliers (32-Bit Results)
  - Load-Store Architecture With 32 32-Bit General-Purpose Registers
  - Instruction Packing Reduces Code Size
  - All Instructions Conditional
- Instruction Set Features
  - Byte-Addressable (8-, 16-, 32-Bit Data)
  - 32-Bit Address Range
  - 8-Bit Overflow Protection
  - Saturation
  - Bit-Field Extract, Set, Clear
  - Bit-Counting
  - Normalization
- 1M-Bit On-Chip SRAM
  - 512K-Bit Internal Program/Cache (16K 32-Bit Instructions)
  - 512K-Bit Dual-Access Internal Data (64K Bytes) Organized as Two Blocks for Improved Concurrency
- 32-Bit External Memory Interface (EMIF)
  - Glueless Interface to Synchronous Memories: SDRAM and SBSRAM
  - Glueless Interface to Asynchronous Memories: SRAM and EPROM
- Four-Channel Bootloading Direct-Memory-Access (DMA) Controller with an Auxiliary Channel
- 16-Bit Host-Port Interface (HPI)
  - Access to Entire Memory Map

#### GLP 429-PIN BALL GRID ARRAY (BGA) PACKAGE (BOTTOM VIEW)



- Two Multichannel Buffered Serial Ports (McBSPs)
  - Direct Interface to T1/E1, MVIP, SCSA Framers
  - ST-Bus-Switching Compatible
  - Up to 256 Channels Each
  - AC97-Compatible
  - Serial Peripheral Interface (SPI)
     Compatible (Motorola™)
- Two 32-Bit General-Purpose Timers
- Flexible Phase-Locked Loop (PLL) Clock Generator
- IEEE-1149.1 (JTAG†) Boundary-Scan Compatible
- 429-Pin BGA Package (GLP Suffix)
- CMOS Technology
  - 0.18-μm/5-Level Metal Process
- 3.3-V I/Os. 1.8-V Internal



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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† IEEE Standard 1149.1-1990 Standard-Test-Access Port and Boundary Scan Architecture.



#### description

The 320C6201B DSP is a member of the fixed-point DSP family in the 320C6000 platform. The SM/SMJ320C6201B ('C6201B) device is based on the high-performance, advanced VelociTI very-long-instruction-word (VLIW) architecture developed by Texas Instruments (TI™), making this DSP an excellent choice for multichannel and multifunction applications. With performance of up to 1600 million instructions per second (MIPS) at a clock rate of 200 MHz, the 'C6201B offers cost-effective solutions to high-performance DSP programming challenges. The 'C6201B is a newer revision of the 'C6201. The 'C6201B DSP possesses the operational flexibility of high-speed controllers and the numerical capability of array processors. This processor has 32 general-purpose registers of 32-bit word length and eight highly independent functional units. The eight functional units provide six arithmetic logic units (ALUs) for a high degree of parallelism and two 16-bit multipliers for a 32-bit result. The 'C6201B can produce two multiply-accumulates (MACs) per cycle—for a total of 400 million MACs per second (MMACS). The 'C6201B DSP also has application-specific hardware logic, on-chip memory, and additional on-chip peripherals.

The 'C6201B includes a large bank of on-chip memory and has a powerful and diverse set of peripherals. Program memory consists of a 64K-byte block that is user-configurable as cache or memory-mapped program space. Data memory of the 'C6201B consists of two 32K-byte blocks of RAM for improved concurrency. The peripheral set includes two multichannel buffered serial ports (McBSPs), two general-purpose timers, a host-port interface (HPI), and a glueless external memory interface (EMIF) capable of interfacing to SDRAM or SBSRAM and asynchronous peripherals.

The 'C6201B has a complete set of development tools which includes: a new C compiler, a third-party Ada 95 compiler, an assembly optimizer to simplify programming and scheduling, and a Windows™ debugger interface for visibility into source code execution.

#### device characteristics

Table 1 provides an overview of the 'C62x DSP. The table shows significant features of each device, including the capacity of on-chip RAM, the peripherals, the execution time, and the package type with pin count.

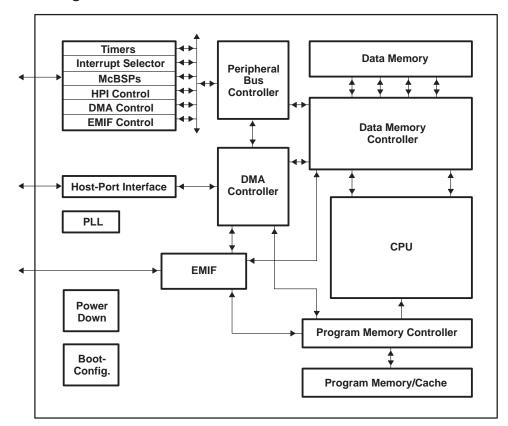
Table 1. Characteristics of the 'C6201B Processor

CHARACTERISTICS	DESCRIPTION
Device Number	320C6201B
On-Chip Memory	512-Kbit Program Memory 512-Kbit Data Memory (organized as two blocks)
Peripherals	2 Multichannel Buffered Serial Ports (McBSPs) 2 General-Purpose Timers Host-Port Interface (HPI) External Memory Interface (EMIF)
Cycle Time	6.7 ns (320C6201B 150 MHz), 5 ns (320C6201B 200 MHz)
Package Type	27 mm × 27 mm, 429-Pin Ceramic D-BGA (GLP)
Nominal Voltage	1.8 V Core 3.3 V I/O

TI is a trademark of Texas Instruments Incorporated. Windows is a registered trademark of the Microsoft Corporation.



# functional block diagram



# SM320C6201B, SMJ320C6201B DIGITAL SIGNAL PROCESSOR

SGUS031 - APRIL 2000

## **CPU** description

The CPU fetches VelociTI advanced very-long instruction words (VLIW) (256 bits wide) to supply up to eight 32-bit instructions to the eight functional units during every clock cycle. The VelociTI VLIW architecture features controls by which all eight units do not have to be supplied with instructions if they are not ready to execute. The first bit of every 32-bit instruction determines if the next instruction belongs to the same execute packet as the previous instruction, or whether it should be executed in the following clock as a part of the next execute packet. Fetch packets are always 256 bits wide; however, the execute packets can vary in size. The variable-length execute packets are a key memory-saving feature, distinguishing the 'C62x CPU from other VLIW architectures.

The CPU features two sets of functional units. Each set contains four units and a register file. One set contains functional units .L1, .S1, .M1, and .D1; the other set contains units .D2, .M2, .S2, and .L2. The two register files each contain 16 32-bit registers for a total of 32 general-purpose registers. The two sets of functional units, along with two register files, compose sides A and B of the CPU (see Figure 1 and Figure 2). The four functional units on each side of the CPU can freely share the 16 registers belonging to that side. Additionally, each side features a single data bus connected to all the registers on the other side, by which the two sets of functional units can access data from the register files on the opposite side. While register access by functional units on the same side of the CPU as the register file can service all the units in a single clock cycle, register access using the register file across the CPU supports one read and one write per cycle.

Another key feature of the 'C62x CPU is the load/store architecture, where all instructions operate on registers (as opposed to data in memory). Two sets of data-addressing units (.D1 and .D2) are responsible for all data transfers between the register files and the memory. The data address driven by the .D units allows data addresses generated from one register file to be used to load or store data to or from the other register file. The 'C62x CPU supports a variety of indirect addressing modes using either linear- or circular-addressing modes with 5- or 15-bit offsets. All instructions are conditional, and most can access any one of the 32 registers. Some registers, however, are singled out to support specific addressing or to hold the condition for conditional instructions (if the condition is not automatically "true"). The two .M functional units are dedicated for multiplies. The two .S and .L functional units perform a general set of arithmetic, logical, and branch functions with results available every clock cycle.

The processing flow begins when a 256-bit-wide instruction fetch packet is fetched from a program memory. The 32-bit instructions destined for the individual functional units are "linked" together by "1" bits in the least significant bit (LSB) position of the instructions. The instructions that are "chained" together for simultaneous execution (up to eight in total) compose an execute packet. A "0" in the LSB of an instruction breaks the chain, effectively placing the instructions that follow it in the next execute packet. If an execute packet crosses the fetch packet boundary (256 bits wide), the assembler places it in the next fetch packet, while the remainder of the current fetch packet is padded with NOP instructions. The number of execute packets within a fetch packet can vary from one to eight. Execute packets are dispatched to their respective functional units at the rate of one per clock cycle and the next 256-bit fetch packet is not fetched until all the execute packets from the current fetch packet have been dispatched. After decoding, the instructions simultaneously drive all active functional units for a maximum execution rate of eight instructions every clock cycle. While most results are stored in 32-bit registers, they can be subsequently moved to memory as bytes or half-words as well. All load and store instructions are byte-, half-word, or word-addressable.

## **CPU** description (continued)

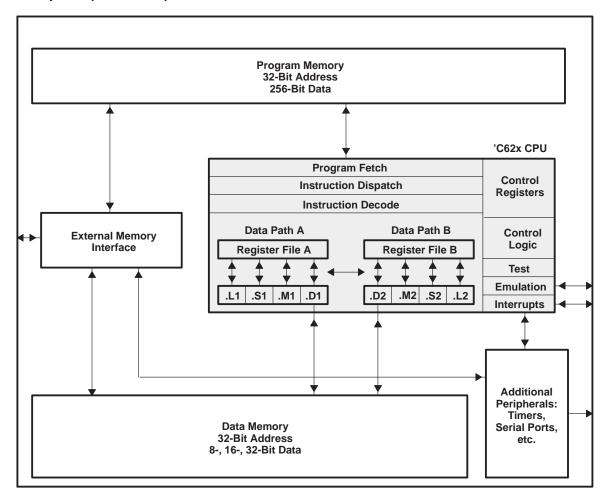


Figure 1. 320C62x CPU Block Diagram

## **CPU** description (continued)

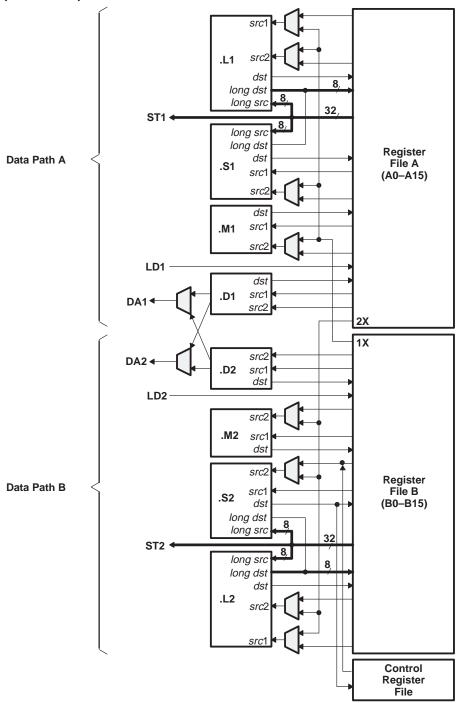


Figure 2. 320C62x CPU Data Paths

## signal groups description

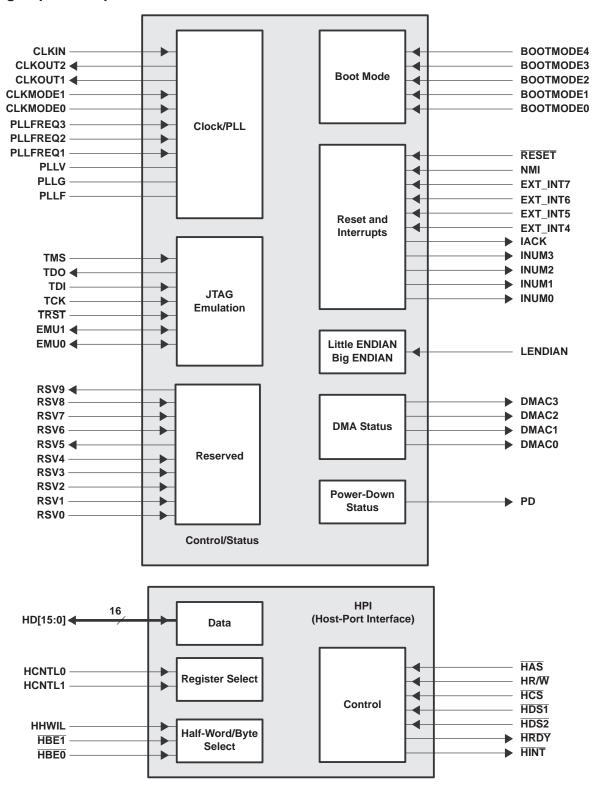


Figure 3. CPU and Peripheral Signals



## signal groups description (continued)

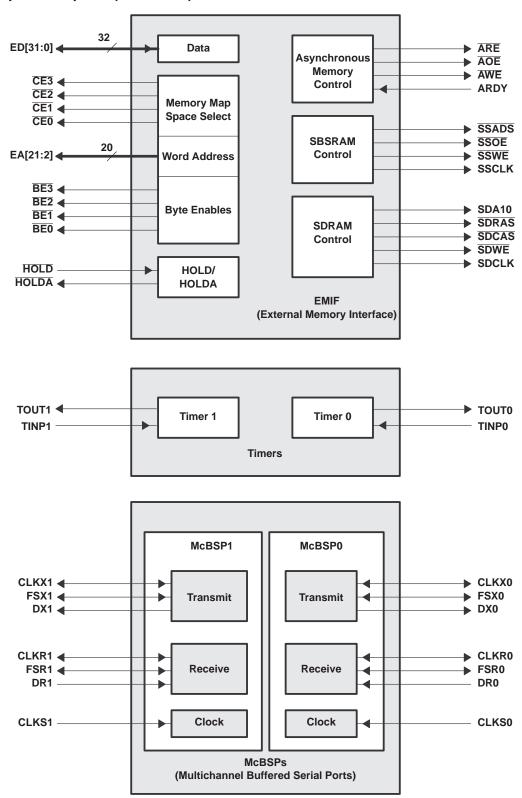


Figure 4. Peripheral Signals



## **Signal Descriptions**

SIGNA NAME	L NO.	TYPE†	DESCRIPTION				
	CLOCK/PLL						
CLKIN	A14	I	Clock Input				
CLKOUT1	Y6	0	Clock output at full device speed				
CLKOUT2	V9	0	Clock output at half of device speed				
CLKMODE1	B17		Clock mode select				
CLKMODE0	C17	1 '	Selects whether the output clock frequency = input clock freq x4 or x1				
PLLFREQ3	C13		PLL frequency range (3, 2, and 1)				
PLLFREQ2	G11	ı	The target range for CLKOUT1 frequency is determined by the 3-bit value of the PLLFREQ pins.				
PLLFREQ1	F11	1					
PLLV <sup>‡</sup>	D12	Α§	PLL analog V <sub>CC</sub> connection for the low-pass filter				
PLLG <sup>‡</sup>	G10	Α§	PLL analog GND connection for the low-pass filter				
PLLF	C12	Α§	PLL low-pass filter connection to external components and a bypass capacitor				
		•	JTAG EMULATION				
TMS	K19	ı	JTAG test port mode select (features an internal pull-up)				
TDO	R12	O/Z	JTAG test port data out				
TDI	R13	ı	JTAG test port data in (features an internal pull-up)				
TCK	M20	ı	JTAG test port clock				
TRST	N18	ı	JTAG test port reset (features an internal pull-down)				
EMU1	R20	I/O/Z	Emulation pin 1, pull-up with a dedicated 20-kΩ resistor				
EMU0	T18	I/O/Z	Emulation pin 0, pull-up with a dedicated 20-kΩ resistor				
		•	RESET AND INTERRUPTS				
RESET	J20	I	Device reset				
NMI	K21	I	Nonmaskable interrupt  • Edge-driven (rising edge)				
EXT_INT7	R16						
EXT_INT6	P20	1.	External interrupts				
EXT_INT5	R15	] '	Edge-driven (rising edge)				
EXT_INT4	R18	1					
IACK	R11	0	Interrupt acknowledge for all active interrupts serviced by the CPU				
INUM3	T19						
INUM2	T20	] _	Active interrupt identification number				
INUM1	T14	0	Valid during IACK for all active interrupts (not just external)     Encoding order follows the interrupt service fetch packet ordering				
INUM0	T16		5				
			LITTLE ENDIAN/BIG ENDIAN				
LENDIAN	G20	I	If high, selects little-endian byte/half-word addressing order within a word If low, selects big-endian addressing				
			POWER DOWN STATUS				
PD	D19	0	Power-down mode 2 or 3 (active if high)				

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground



<sup>&</sup>lt;sup>‡</sup> PLLV and PLLG signals are not part of external voltage supply or ground. See the CLOCK/PLL documentation for information on how to connect those pins.

<sup>§</sup> A = Analog Signal (PLL Filter)

SIGNAL NAME	NO.	TYPE†	DESCRIPTION
10,1112			HOST PORT INTERFACE (HPI)
HINT	H2	O/Z	Host interrupt (from DSP to host)
HCNTL1	J6	I	Host control – selects between control, address or data registers
HCNTL0	H6	I	Host control – selects between control, address or data registers
HHWIL	E4	I	Host halfword select – first or second halfword (not necessarily high or low order)
HBE1	G6	I	Host byte select within word or half-word
HBE0	F6	I	Host byte select within word or half-word
HR/W	D4	I	Host read or write select
HD15	D11		
HD14	B11		
HD13	A11		
HD12	G9		
HD11	D10		
HD10	A10		Host port data (used for transfer of data, address and control)
HD9	C10		
HD8	В9	1/0/7	
HD7	F9	I/O/Z	
HD6	C9		
HD5	A9		
HD4	B8		
HD3	D9		
HD2	D8		
HD1	B7		
HD0	C7		
HAS	L6	- 1	Host address strobe
HCS	C5	- 1	Host chip select
HDS1	C4	- 1	Host data strobe 1
HDS2	K6	- 1	Host data strobe 2
HRDY	НЗ	0	Host ready (from DSP to host)
			BOOT MODE
BOOTMODE4	B16		
BOOTMODE3	G14		
BOOTMODE2	F15	I	Boot mode
BOOTMODE1	C18		
BOOTMODE0	D17		

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground



SIGNA		TYPE†	DESCRIPTION
NAME	NO.		
			MIF – CONTROL SIGNALS COMMON TO ALL TYPES OF MEMORY
CE3	Y5	O/Z	
CE2	V3	O/Z	Memory space enables
CE1	T6	O/Z	Enabled by bits 24 and 25 of the word address
CE0	U2	O/Z	Only one asserted during any external data access
BE3	R8	O/Z	Byte enable control
BE2	T3	O/Z	Decoded from the two lowest bits of the internal address
BE1	T2	O/Z	Byte write enables for most types of memory
BE0	R2	O/Z	Can be directly connected to SDRAM read and write mask signal (SDQM)
		_	EMIF – ADDRESS
EA21	L4		
EA20	L3		
EA19	J2		
EA18	J1		
EA17	K1		
EA16	K2		
EA15	L2		
EA14	L1		
EA13	M1		
EA12	M2		
EA11	M6	O/Z	External address (word address)
EA10	N4		
EA9	N1		
EA8	N2		
EA7	N6		
EA6	P4		
EA5	P3		
EA4	P2		
EA3	P1		
EA2	P6		

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

SIGN	IAL	_	orginal Descriptions (Continued)
NAME	NO.	TYPE†	DESCRIPTION
			EMIF – DATA
ED31	U18		
ED30	U20		
ED29	T15		
ED28	V18		
ED27	V17		
ED26	V16		
ED25	T12		
ED24	W17		
ED23	T13		
ED22	Y17		
ED21	T11		
ED20	Y16		
ED19	W15		
ED18	V14		
ED17	Y15		
ED16	R9		
ED15	Y14	I/O/Z	External data
ED14	V13		
ED13	AA13		
ED12	T10		
ED11	Y13		
ED10	W12		
ED9	Y12		
ED8	Y11		
ED7	V10		
ED6	AA10		
ED5	Y10		
ED4	W10		
ED3	Y9		
ED2	AA9		
ED1	Y8		
ED0	W9		
			EMIF – ASYNCHRONOUS MEMORY CONTROL
ARE	R7	O/Z	Asynchronous memory read enable
AOE	T7	O/Z	Asynchronous memory output enable
AWE	V5	O/Z	Asynchronous memory write enable
ARDY	R4	I	Asynchronous memory ready input

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground



SIGNA		TYPE†	DESCRIPTION
NAME	NO.	11112	
		I	EMIF – SYNCHRONOUS BURST SRAM CONTROL
SSADS	V8	O/Z	SBSRAM address strobe
SSOE	W7	O/Z	SBSRAM output enable
SSWE	Y7	O/Z	SBSRAM write enable
SSCLK	AA8	O/Z	SBSRAM clock
			EMIF – SYNCHRONOUS DRAM CONTROL
SDA10	V7	O/Z	SDRAM address 10 (separate for deactivate command)
SDRAS	V6	O/Z	SDRAM row address strobe
SDCAS	W5	O/Z	SDRAM column address strobe
SDWE	T8	O/Z	SDRAM write enable
SDCLK	Т9	O/Z	SDRAM clock
			EMIF – BUS ARBITRATION
HOLD	R6	I	Hold request from the host
HOLDA	B15	0	Hold request acknowledge to the host
			TIMERS
TOUT1	G2	O/Z	Timer 1 or general-purpose output
TINP1	K3	I	Timer 1 or general-purpose input
TOUT0	M18	O/Z	Timer 0 or general-purpose output
TINP0	J18	I	Timer 0 or general-purpose input
		-	DMA ACTION COMPLETE
DMAC3	E18		
DMAC2	F19	]	
DMAC1	E20	0	DMA action complete
DMAC0	G16	1	
		-	MULTICHANNEL BUFFERED SERIAL PORT 1 (McBSP1)
CLKS1	F4	I	External clock source (as opposed to internal)
CLKR1	H4	I/O/Z	Receive clock
CLKX1	J4	I/O/Z	Transmit clock
DR1	E2	ı	Receive data
DX1	G4	O/Z	Transmit data
FSR1	F3	I/O/Z	Receive frame sync
FSX1	F2	I/O/Z	Transmit frame sync

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

SIGNAL	_	T./DE#	DESCRIPTION
NAME	NO.	TYPE†	DESCRIPTION
			MULTICHANNEL BUFFERED SERIAL PORT 0 (McBSP0)
CLKS0	K18	I	External clock source (as opposed to internal)
CLKR0	L21	I/O/Z	Receive clock
CLKX0	K20	I/O/Z	Transmit clock
DR0	J21	I	Receive data
DX0	M21	O/Z	Transmit data
FSR0	P16	I/O/Z	Receive frame sync
FSX0	N16	I/O/Z	Transmit frame sync
			RESERVED FOR TEST
RSV0	N21	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor
RSV1	K16	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor
RSV2	B13	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor
RSV3	B14	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor
RSV4	F13	I	Reserved for testing, $\emph{pull-down}$ with a dedicated 20-k $\Omega$ resistor
RSV5	C15	0	Reserved (leave unconnected, do not connect to power or ground)
RSV6	F7	I	Reserved for testing, pull-up with a dedicated 20-kΩ resistor
RSV7	D7	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor
RSV8	B5	I	Reserved for testing, pull-up with a dedicated 20-k $\Omega$ resistor
RSV9	F16	0	Reserved (leave unconnected, <i>do not</i> connect to power or ground)
			SUPPLY VOLTAGE PINS
	C14		
	C8		
	E19		
	E3		
	H11		
	H13		
	H9		
	J10		
	J12		
	J14		
$DV_DD$	J19	S	3.3-V supply voltage
	J3		
	J8		
	K11		
	K13		
	K15		
	K7		
	K9		
	L10		
	L12		
	L14		

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground



SIGNA	SIGNAL SI						
NAME	NO.	TYPE†	DESCRIPTION				
	SUPPLY VOLTAGE PINS (CONTINUED)						
	L8						
	M11	$\exists$					
	M13						
	M15						
	M7						
	M9						
	N10						
	N12						
	N14						
$DV_DD$	N19	s	3.3-V supply voltage				
	N3						
	N8						
	P11						
	P13						
	P9						
	U19						
	U3						
	W14						
	W8						
	A12						
	A13						
	B10						
	B12						
	В6						
	D15						
	D16						
	F10						
	F14						
CV <sub>DD</sub>	F8	S	1.8-V supply voltage				
	G13						
	G7						
	G8						
	K4						
	M3						
	M4	4					
	A3						
	A5						
		A7					
	A16						

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

SIGNAI		TYPE†	DESCRIPTION
NAME	NO.		SUPPLY VOLTAGE PINS (CONTINUED)
	A18		SUPPLY VOLIAGE PINS (CONTINUED)
	AA4		
	AA6		
	AA15		
	AA17		
	AA19		
	B2		
	B4		
	B19		
	C1		
	C3		
	C20		
	D2		
	D21 E1		
	E6		
	E8		
CV <sub>DD</sub>	E10	S	1.8-V supply voltage
	E12		
	E14		
	E16		
	F5		
	F17		
	F21		
	G1		
	H5		
	H17		
	K5		
	K17		
	M5		
	M17 P5		
	P17		
	R21		

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

SIGNAL			Signal Descriptions (Continued)
NAME N	NO.	TYPE†	DESCRIPTION
			SUPPLY VOLTAGE PINS (CONTINUED)
CV <sub>DD</sub> A A F G G H L L L L L L L L L L L L L L L L L	T1	S	1.8-V supply voltage

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

SIGNAI	_		DESCRIPTION
NAME	NO.	TYPE†	DESCRIPTION
			GROUND PINS
	C11		
	C16		
	C6		
	D5		
	G3		
	H10		
	H12		
	H14		
	H7		
	H8		
	J11		
	J13		
	J7		
	J9		
	K8		
	L7		
	L9		
	M8		
	N7		
V <sub>SS</sub>	R3	GND	Ground pins
	A4		
	A6		
	A8		
	A15		
	A17		
	A19		
	AA3		
	AA5		
	AA7		
	AA14		
	AA16		
	AA18		
	В3		
	B18		
	B20		
	C2		
	C19		
	C21		
	D1		

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground



SIGNA	L	TYPE†	DESCRIPTION
NAME	NO.		GROUND PINS (CONTINUED)
	D20		CROOKE FINE (GORTINGLE)
	E5		
	E7		
	E9		
	E11		
	E13		
	E15		
	E17		
	E21		
	F1		
	G5		
	G17		
	G21 H1		
	J5		
	J17		
	L5		
$V_{SS}$	L17	GND	Ground pins
- 33	N5		
	N17		
	P21		
	R1		
	R5		
	R17		
	T21		
	U1		
	U5		
	U7		
	U9		
	U11 U13		
	U15		
	U17		
	V2	1	
	V21		

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

SIGNAI		TYPE†	DESCRIPTION
NAME	NO.	=	GROUND PINS (CONTINUED)
	W1		GROUND FINS (CONTINUED)
	W3		
	W20		
	Y2		
	Y4		
	Y19		
	F18		
	G19		
	H15		
	J15		
	J16		
	K10		
	K12		
	K14	14	
	L11		
	L13		
	L15		
$V_{SS}$	M10	GND	Ground pins
	M12		
	M14		
	N11		
	N13		
	N15		
	N9		
	P10 P12		
	P12		
	P15		
	P7		
	P8		
	R19		
	T4		
	W11		
	W16		
	W6		

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

SIGNAI NAME	NO.	TYPE†	DESCRIPTION
			REMAINING UNCONNECTED PINS
	D13		
	D14	1	
	D18	]	
	D3		
	D6		
	F12		
	G12		
	G15		
NC	H19		Unconnected pins
INC	H20	]	onconnected pins
	H21	]	
	L16	]	
	M16	]	
	M19		
	V19		
	V4		
	W18		
	W4		

<sup>†</sup> I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

### development support

Texas Instruments offers an extensive line of development tools for the 'C6000 generation of DSPs, including tools to evaluate the performance of the processors, generate code, develop algorithm implementations, and fully integrate and debug software and hardware modules.

The following products support development of 'C6000-based applications:

#### **Software Development Tools:**

Assembly optimizer Assembler/Linker Simulator Optimizing ANSI C compiler Application algorithms C/Assembly debugger and code profiler

#### **Hardware Development Tools:**

Extended development system (XDS™) emulator (supports 'C6000 multiprocessor system debug) EVM (Evaluation Module)

The TMS320 DSP Development Support Reference Guide (SPRU011) contains information about development-support products for all TMS320 family member devices, including documentation. See this document for further information on TMS320 documentation or any TMS320 support products from Texas Instruments. An additional document, the TMS320 Third-Party Support Reference Guide (SPRU052), contains information about TMS320-related products from other companies in the industry. To receive TMS320 literature, contact the Product Information Center at (800) 477-8924.

See Table 2 for a complete listing of development-support tools for the 'C6000. For information on pricing and availability, contact the nearest TI field sales office or authorized distributor.

Table 2. 320C6000 Development-Support Tools

DEVELOPMENT TOOL	PLATFORM	PART NUMBER
	Software	
Ada 95 Compiler <sup>†</sup>	Sun Solaris 2.3™ <sup>‡</sup>	AD0345AS8500RF - Single User AD0345BS8500RF - Multi-user
C Compiler/Assembler/Linker/Assembly Optimizer	Win32™	TMDX3246855-07
C Compiler/Assembler/Linker/Assembly Optimizer	SPARC™ Solaris™	TMDX324655-07
Simulator	Win32	TMDS3246851-07
Simulator	SPARC Solaris	TMDS3246551-07
XDS510™ Debugger/Emulation Software	Win32, Windows NT™	TMDX324016X-07
	Hardware	
XDS510 Emulator§	PC	TMDS00510
XDS510WS™ Emulator¶	SCSI	TMDS00510WS
	Software/Hardware	
EVM Evaluation Kit	PC/Win95/Windows NT	TMDX3260A6201
EVM Evaluation Kit (including TMDX3246855–07)	PC/Win95/Windows NT	TMDX326006201

<sup>&</sup>lt;sup>†</sup> Contact IRVINE Compiler Corporation (949) 250-1366 to order.

XDS, XDS510, and XDS510WS are trademarks of Texas Instruments Incorporated. Win32 and Windows NT are trademarks of Microsoft Corporation. SPARC is a trademark of SPARC International, Inc. Solaris is a trademark of Sun Microsystems, Inc.



<sup>&</sup>lt;sup>‡</sup> NT support estimated availability 1Q00.

<sup>§</sup> Includes XDS510 board and JTAG emulation cable. TMDX324016X-07 C-source Debugger/Emulation software is not included.

Includes XDS510WS box, SCSI cable, power supply, and JTAG emulation cable.

#### device and development-support tool nomenclature

To designate the stages in the product development cycle, TI assigns prefixes to the part numbers of all TMS320 devices and support tools. Each TMS320 member has one of three prefixes: SMX, SM, or SMJ. Texas Instruments recommends two of three possible prefix designators for support tools: TMDX and TMDS. These prefixes represent evolutionary stages of product development from engineering prototypes (SMX/TMDX) through fully qualified production devices/tools (SMJ/TMDS). This development flow follows.

Device development evolutionary flow:

SMX Experimental device that is not necessarily representative of the final device's electrical

specifications, 25°C tested, military/industrial ceramic dimpled Ball Grid Array package

SM Fully TI-qualified production device; offered in extended temperature ranges: -40°C to +90°C (S

range), and -55°C to +115°C (W range); in ceramic dimpled BGA package

**SMJ** Fully SMD-qualified production device, –55°C to +115°C (W temperature range), in the ceramic

dimpled Ball Grid Array package processed to MIL-PRF-38535

Support tool development evolutionary flow:

**TMDX** Development-support product that has not yet completed Texas Instruments internal qualification

testing.

**TMDS** Fully qualified development-support product

TMX and TMP devices and TMDX development-support tools are shipped against the following disclaimer:

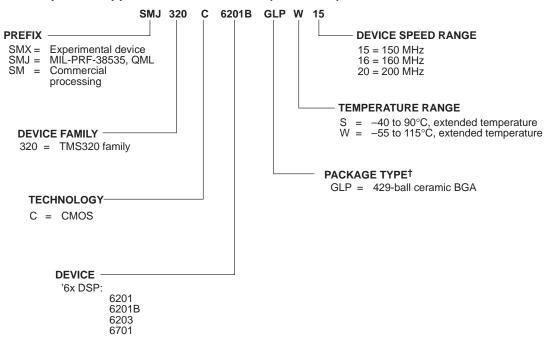
"Developmental product is intended for internal evaluation purposes."

TMS devices and TMDS development-support tools have been characterized fully, and the quality and reliability of the device have been demonstrated fully. Tl's standard warranty applies.

Predictions show that prototype devices (SMX or SM) have a greater failure rate than the standard production devices. Texas Instruments recommends that these devices not be used in any production system because their expected end-use failure rate still is undefined. Only qualified production devices are to be used.

TI device nomenclature also includes a suffix with the device family name. This suffix indicates the package type (GLP) and the device speed range in megahertz (for example, 15 is 150 MHz). Figure 5 provides a legend for reading the complete device name.

#### device and development-support tool nomenclature (continued)



†BGA = Ball Grid Array

Figure 5. TMS320 Device Nomenclature (Including SMJ320C6201B)

## documentation support

Extensive documentation supports all TMS320 family generations of devices from product announcement through applications development. The types of documentation available include: data sheets, such as this document, with design specifications; complete user's reference guides for all devices; technical briefs; development-support tools; and hardware and software applications. The following is a brief, descriptive list of support documentation specific to the 'C6x devices:

The TMS320C6000 CPU and Instruction Set Reference Guide (literature number SPRU189) describes the 'C6000 CPU architecture, instruction set, pipeline, and associated interrupts.

The TMS320C6000 Peripherals Reference Guide (literature number SPRU190) describes the functionality of the peripherals available on 'C6x devices, such as the external memory interface (EMIF), host-port interface (HPI), multichannel buffered serial ports (McBSPs), direct-memory-access (DMA), enhanced direct-memory-access (EDMA) controller, expansion bus (XB), clocking and phase-locked loop (PLL); and power-down modes. This guide also includes information on internal data and program memories.

The TMS320C6000 Programmer's Guide (literature number SPRU198) describes ways to optimize C and assembly code for 'C6x devices and includes application program examples.

The TMS320C6x C Source Debugger User's Guide (literature number SPRU188) describes how to invoke the 'C6x simulator and emulator versions of the C source debugger interface and discusses various aspects of the debugger, including: command entry, code execution, data management, breakpoints, profiling, and analysis.

The TMS320C6x Peripheral Support Library Programmer's Reference (literature number SPRU273) describes the contents of the 'C6x peripheral support library of functions and macros. It lists functions and macros both by header file and alphabetically, provides a complete description of each, and gives code examples to show how they are used.



## documentation support (continued)

TMS320C6000 Assembly Language Tools User's Guide (literature number SPRU186) describes the assembly language tools (assembler, linker, and other tools used to develop assembly language code), assembler directives, macros, common object file format, and symbolic debugging directives for the 'C6000 generation of devices.

The TMS320C6x Evaluation Module Reference Guide (literature number SPRU269) provides instructions for installing and operating the 'C6x evaluation module. It also includes support software documentation, application programming interfaces, and technical reference material.

TMS320C62x Multichannel Evaluation Module User's Guide (literature number SPRU285) provides instructions for installing and operating the 'C62x multichannel evaluation module. It also includes support software documentation, application programming interfaces, and technical reference material.

TMS320C62x Multichannel Evaluation Module Technical Reference (SPRU308) provides provides technical reference information for the 'C62x multichannel evaluation module (McEVM). It includes support software documentation, application programming interface references, and hardware descriptions for the 'C62x McEVM.

*TMS320C6000 DSP/BIOS User's Guide* (literature number SPRU303) describes how to use DSP/BIOS tools and APIs to analyze embedded real-time DSP applications.

Code Composer User's Guide (literature number SPRU296) explains how to use the Code Composer development environment to build and debug embedded real-time DSP applications.

Code Composer Studio Tutorial (literature number SPRU301) introduces the Code Composer Studio integrated development environment and software tools.

The *TMS320C6000 Technical Brief* (literature number SPRU197) gives an introduction to the 'C62x/C67x devices, associated development tools, and third-party support.

A series of DSP textbooks is published by Prentice-Hall and John Wiley & Sons to support DSP research and education. The TMS320 newsletter, *Details on Signal Processing*, is published quarterly and distributed to update TMS320 customers on product information. The TMS320 DSP bulletin board service (BBS) provides access to information pertaining to the TMS320 family, including documentation, source code, and object code for many DSP algorithms and utilities. The BBS can be reached at 281/274-2323.

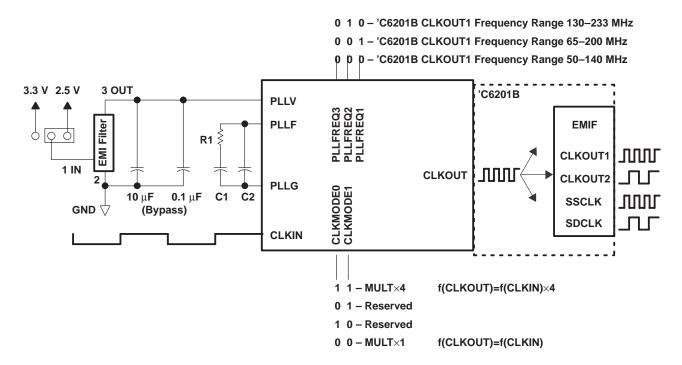
Information regarding TI DSP products is also available on the Worldwide Web at http://www.ti.com uniform resource locator (URL).

#### clock PLL

All of the 'C62x clocks are generated from a single source through the CLKIN pin. This source clock either drives the PLL, which generates the internal CPU clock, or bypasses the PLL to become the CPU clock.

To use the PLL to generate the CPU clock, the filter circuit shown in Figure 6 must be properly designed. For the 'C6201B, it must be powered by the I/O voltage (3.3 V).

To configure the 'C62x PLL clock for proper operation, see Figure 6 and Table 3. To minimize the clock jitter, a single clean power supply should power both the 'C62x device and the external clock oscillator circuit. The minimum CLKIN rise and fall times should also be observed. See the *input and output clocks* section for input clock timing requirements.



- NOTES: A. For the 'C6201B CLKMODE x4, values for C1, C2, and R1 are fixed and apply to all valid frequency ranges of CLKIN and CLKOUT.
  - B. For CLKMODE x1, the PLL is bypassed and all six external PLL components can be removed. For this case, the PLLV terminal has to be connected to a clean supply and the PLLG and PLLF terminals should be tied together.
  - C. Due to overlap of frequency ranges when choosing the PLLFREQ, more than one frequency range can contain the CLKOUT1 frequency. Choose the lowest frequency range that includes the desired frequency. For example, for CLKOUT1 = 133 MHz, a PLLFREQ value of 000b should be used for the 'C6201B. For CLKOUT1 = 200 MHz, PLLFREQ should be set to 001b for the 'C6201B. PLLFREQ values other than 000b, 001b, and 010b are reserved.
  - D. For the 'C6201B, the 3.3-V supply for the EMI filter (and PLLV) must be from the same 3.3-V power plane supplying the I/O voltage, DV<sub>DD</sub>.

Figure 6. PLL Block Diagram



## clock PLL (continued)

Table 3. 320C6201B PLL Component Selection Table

	CLKMODE	CLKIN RANGE (MHz)	CPU CLOCK FREQUENCY (CLKOUT1) RANGE (MHz)	CLKOUT2 RANGE (MHz)	R1 (Ω)	C1 (nF)	C2 (pF)	TYPICAL LOCK TIME (μs) <sup>†</sup>
L	x4	12.5–50	50-200	25-100	60.4	27	560	75

<sup>&</sup>lt;sup>†</sup> Under some operating conditions, the maximum PLL lock time may vary as much as 150% from the specified typical value. For example, if the typical lock time is specified as 100 μs, the maximum value may be as long as 250 μs.

## power supply sequencing

For the 'C6201B device, the 1.8-V supply powers the core and the 3.3-V supply powers the I/O buffers. The core supply should be powered up first, or at the same time as the I/O buffers. This is to ensure that the I/O buffers have valid inputs from the core before the output buffers are powered up, thus preventing bus contention with other chips on the board.

# SM320C6201B, SMJ320C6201B DIGITAL SIGNAL PROCESSOR

SGUS031 - APRIL 2000

## absolute maximum ratings over operating case temperature range (unless otherwise noted)†

Supply voltage range, CV <sub>DD</sub> (see Note 1)	–0.3 V to 2.3 V
Supply voltage range, DV <sub>DD</sub> (see Note 1)	0.3 V to 4 V
Input voltage range	0.3 V to 4 V
Output voltage range	0.3 V to 4 V
Operating case temperature range T <sub>C</sub> : (S temp version)	—40°C to 90°C
(W temp version)	
Storage temperature range, T <sub>stg</sub>	–55°C to 150°C

<sup>&</sup>lt;sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

# NOTE 1: All voltage values are with respect to $V_{\mbox{\scriptsize SS}}$ .

## recommended operating conditions

				,	C6201B		LINUT
				MIN	NOM	MAX	UNIT
$CV_{DD}$	Supply voltage			1.71	1.8	1.89	V
$DV_DD$	Supply voltage			3.14	3.30	3.46	V
V <sub>SS</sub>	Supply ground			0	0	0	V
$V_{IH}$	High-level input voltage			2.0			V
$V_{IL}$	Low-level input voltage					0.8	V
I <sub>OH</sub>	High-level output current					-12	mA
I <sub>OL</sub>	Low-level output current					12	mA
_	Q	S temp version	_	-40		90	00
T <sub>C</sub>	Operating case temperature <sup>‡</sup>	W temp version		-55		115	°C

<sup>&</sup>lt;sup>‡</sup> Case temperature is measured at package bottom. There is no direct thermal path from the chip through the lid.

# electrical characteristics over recommended ranges of supply voltage and operating case temperature (unless otherwise noted)

			'(	C6201B		
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>OH</sub>	High-level output voltage	$DV_{DD} = MIN,$ $I_{OH} = MAX$	2.4			V
V <sub>OL</sub>	Low-level output voltage	$DV_{DD} = MIN,$ $I_{OL} = MAX$			0.6	V
l <sub>l</sub>	Input current <sup>†</sup>	$V_I = V_{SS}$ to $DV_{DD}$			±10	uA
I <sub>OZ</sub>	Off-state output current	$V_O = DV_{DD}$ or 0 V			±10	uA
I <sub>DD2V</sub>	Supply current, CPU + CPU memory access‡	CV <sub>DD</sub> = NOM, CPU clock = 167 MHz		380		mA
I <sub>DD2V</sub>	Supply current, peripherals§	CV <sub>DD</sub> = NOM, CPU clock = 167 MHz		240		mA
I <sub>DD3V</sub>	Supply current, I/O pins¶	DV <sub>DD</sub> = NOM, CPU clock = 167 MHz		90		mA
Ci	Input capacitance				15	pF
Co	Output capacitance				15	pF

<sup>&</sup>lt;sup>†</sup> TMS and TDI are not included due to internal pullups.

TRST is not included due to internal pulldown.

<sup>‡</sup> Measured with average CPU activity:

50% of time: 8 instructions per cycle, 32-bit DMEM access per cycle 50% of time: 2 instructions per cycle, 16-bit DMEM access per cycle

§ Measured with average peripheral activity:

50% of time: Timers at max rate, McBSPs at E1 rate, and DMA burst transfer between DMEM and SDRAM

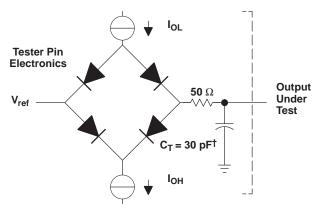
50% of time: Timers at max rate, McBSPs at E1 rate, and DMA servicing McBSPs

¶ Measured with average I/O activity (30-pF load): 25% of time: Reads from external SDRAM 25% of time: Writes to external SDRAM

50% of time: No activity



## PARAMETER MEASUREMENT INFORMATION



<sup>&</sup>lt;sup>†</sup> Typical distributed load circuit capacitance

Figure 7. TTL-Level Outputs

## signal transition levels

All input and output timing parameters are referenced to 1.5 V for both "0" and "1" logic levels.

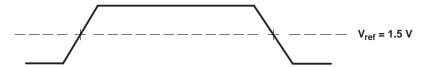


Figure 8. Input and Output Voltage Reference Levels for AC Timing Measurements

## INPUT AND OUTPUT CLOCKS

## timing requirements for CLKIN (see Figure 9)

				'C620	1B-15			'C620	1B-20		
NO.			CLKN = 2	-	CLKM = X	-	CLKN = 3	_	CLKM = X	_	UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
1	t <sub>c(CLKIN)</sub>	Cycle time, CLKIN	26.7		6.67		20	.ć.	5	4	ns
2	t <sub>w(CLKINH)</sub>	Pulse duration, CLKIN high	*9.8		*2.7		*8	SIM	*2.35	J. W	ns
3	t <sub>w(CLKINL)</sub>	Pulse duration, CLKIN low	*9.8		*2.7		*8	7	*2.35	7	ns
4	t <sub>t(CLKIN)</sub>	Transition time, CLKIN	·	*5		*0.6	Q.	*5	.6,	*0.6	ns

<sup>\*</sup>Not production tested.

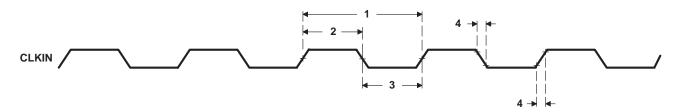


Figure 9. CLKIN Timings

# switching characteristics for CLKOUT1<sup>†‡</sup> (see Figure 10)

				'C62	01B		
NO.		PARAMETER CLKMODE = x4 CLKMODE = x		NODE = x4 CLK		E = x1	UNIT
			MIN	MAX	MIN	MAX	
1	t <sub>c(CKO1)</sub>	Cycle time, CLKOUT1	*P - 0.7	*P + 0.7	*P - 0.7	*P + 0.7	ns
2	t <sub>w(CKO1H)</sub>	Pulse duration, CLKOUT1 high	*(P/2) - 0.5	*(P/2) + 0.5	*PH – 0.5	*PH + 0.5	ns
3	t <sub>w(CKO1L)</sub>	Pulse duration, CLKOUT1 low	*(P/2) - 0.5	*(P/2) + 0.5	*PL - 0.5	*PL + 0.5	ns
4	t <sub>t(CKO1)</sub>	Transition time, CLKOUT1		*0.6		*0.6	ns

 $<sup>^\</sup>dagger$  PH is the high period of CLKIN in ns and PL is the low period of CLKIN in ns.

<sup>\*</sup>Not production tested.

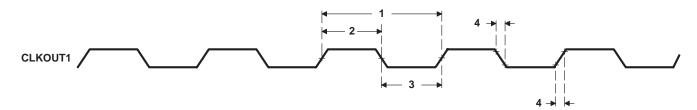


Figure 10. CLKOUT1 Timings

<sup>&</sup>lt;sup>‡</sup> P = 1/CPU clock frequency in nanoseconds (ns).

# **INPUT AND OUTPUT CLOCKS (CONTINUED)**

# switching characteristics for CLKOUT2<sup>†</sup> (see Figure 11)

NO		DADAMETED	'C62	01B	
NO.	. PARAMETER		MIN	MAX	UNIT
1	t <sub>c(CKO2)</sub>	Cycle time, CLKOUT2	*2P – 0.7	*2P + 0.7	ns
2	t <sub>w(CKO2H)</sub>	Pulse duration, CLKOUT2 high	*P - 0.9	*P + 0.7	ns
3	t <sub>w(CKO2L)</sub>	Pulse duration, CLKOUT2 low	*P - 0.7	*P + 0.9	ns
4	t <sub>t(CKO2)</sub>	Transition time, CLKOUT2		*0.6	ns

<sup>†</sup> P = 1/CPU clock frequency in ns.

<sup>\*</sup>Not production tested.

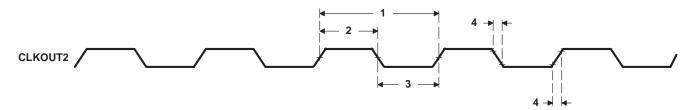


Figure 11. CLKOUT2 Timings

## **INPUT AND OUTPUT CLOCKS (CONTINUED)**

## **SDCLK**, **SSCLK** timing parameters

SDCLK timing parameters are the same as CLKOUT2 parameters.

SSCLK timing parameters are the same as CLKOUT1 or CLKOUT2 parameters, depending on SSCLK configuration.

# switching characteristics for the relation of SSCLK, SDCLK, and CLKOUT2 to CLKOUT1 (see Figure 12)<sup>†</sup>

			'C62	.01B	
NO.		PARAMETER	MIN	MAX	UNIT
1	t <sub>d(CKO1-SSCLK)</sub>	Delay time, CLKOUT1 edge to SSCLK edge	(P/2) + 0.2	(P/2) + 4.2	ns
2	t <sub>d</sub> (CKO1-SSCLK1/2)	Delay time, CLKOUT1 edge to SSCLK edge (1/2 clock rate)	(P/2) - 1	(P/2) + 2.4	ns
3	t <sub>d(CKO1-CKO2)</sub>	Delay time, CLKOUT1 edge to CLKOUT2 edge	*(P/2) - 1	*(P/2) + 2.4	ns
4	t <sub>d</sub> (CKO1-SDCLK)	Delay time, CLKOUT1 edge to SDCLK edge	(P/2) - 1	(P/2) + 2.4	ns

 $<sup>^{\</sup>dagger}$  P = 1/CPU clock frequency in ns.

<sup>\*</sup>Not production tested.

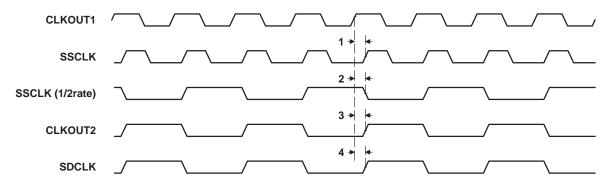


Figure 12. Relation of CLKOUT2, SDCLK, and SSCLK to CLKOUT1

## **ASYNCHRONOUS MEMORY TIMING**

# timing requirements for asynchronous memory cycles<sup>†</sup> (see Figure 13 and Figure 14)

No			'C620		
NO.			MIN	MAX	UNIT
6	t <sub>su(EDV-CKO1H)</sub>	Setup time, read EDx valid before CLKOUT1 high	4.0		ns
7	t <sub>h(CKO1H-EDV)</sub>	Hold time, read EDx valid after CLKOUT1 high	0.8		ns
10	t <sub>su(ARDY-CKO1H)</sub>	Setup time, ARDY valid before CLKOUT1 high	3.0		ns
11	t <sub>h</sub> (CKO1H-ARDY)	Hold time, ARDY valid after CLKOUT1 high	1.8		ns

<sup>†</sup> To ensure data setup time, simply program the strobe width wide enough. ARDY is internally synchronized. If ARDY does meet setup or hold time, it may be recognized in the current cycle or the next cycle. Thus, ARDY can be an asynchronous input.

# switching characteristics for asynchronous memory cycles<sup>‡</sup> (see Figure 13 and Figure 14)

NO.	PARAMETER		'C6201B		
			MIN	MAX	UNIT
1	t <sub>d(CKO1H-CEV)</sub>	Delay time, CLKOUT1 high to CEx valid	-0.2	4.0	ns
2	t <sub>d(CKO1H-BEV)</sub>	Delay time, CLKOUT1 high to BEx valid		4.0	ns
3	t <sub>d</sub> (CKO1H-BEIV)	Delay time, CLKOUT1 high to BEx invalid	*-0.2		ns
4	t <sub>d</sub> (CKO1H-EAV)	Delay time, CLKOUT1 high to EAx valid		4.0	ns
5	t <sub>d</sub> (CKO1H-EAIV)	Delay time, CLKOUT1 high to EAx invalid	*-0.2		ns
8	t <sub>d(CKO1H-AOEV)</sub>	Delay time, CLKOUT1 high to AOE valid	-0.2	4.0	ns
9	t <sub>d(CKO1H-AREV)</sub>	Delay time, CLKOUT1 high to ARE valid	-0.2	4.0	ns
12	t <sub>d(CKO1H-EDV)</sub>	Delay time, CLKOUT1 high to EDx valid		4.0	ns
13	t <sub>d</sub> (CKO1H-EDIV)	Delay time, CLKOUT1 high to EDx invalid	*-0.2		ns
14	t <sub>d</sub> (CKO1H-AWEV)	Delay time, CLKOUT1 high to AWE valid	-0.2	4.0	ns

<sup>&</sup>lt;sup>‡</sup> The minimum delay is also the minimum output hold after CLKOUT1 high.



<sup>\*</sup>Not production tested.

## **ASYNCHRONOUS MEMORY TIMING (CONTINUED)**

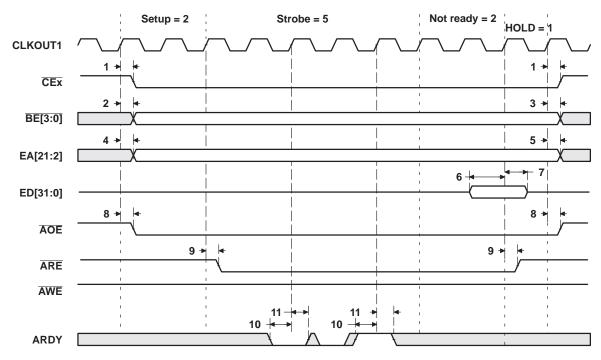


Figure 13. Asynchronous Memory Read Timing

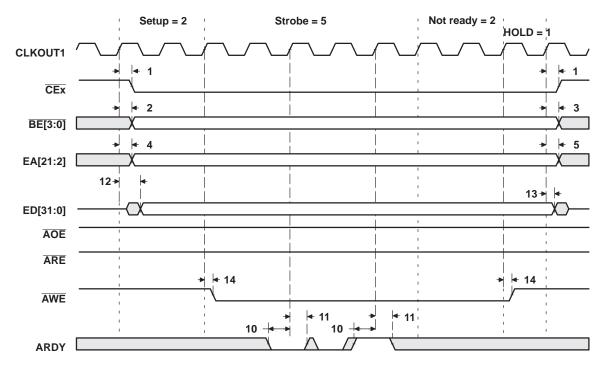


Figure 14. Asynchronous Memory Write Timing



## SYNCHRONOUS-BURST MEMORY TIMING

## timing requirements for synchronous-burst SRAM cycles (full-rate SSCLK) (see Figure 15)

NO.			'C6201B		
NO.			MIN	MAX	UNIT
7	t <sub>su(EDV-SSCLKH)</sub> Setup time, read EDx valid before SSCLK high		1.7		ns
8	t <sub>h(SSCLKH-EDV)</sub> Hold time, read EDx valid after SSCLK high		1.5		ns

# switching characteristics for synchronous-burst SRAM cycles<sup>†</sup> (full-rate SSCLK) (see Figure 15 and Figure 16)

NO.	PARAMETER		'C6201B	UNIT
		MIN MAX		
1	t <sub>osu(CEV-SSCLKH)</sub>	Output setup time, CEx valid before SSCLK high	0.5P - 1.3	ns
2	toh(SSCLKH-CEV)	Output hold time, CEx valid after SSCLK high	0.5P - 2.3	ns
3	t <sub>osu(BEV-SSCLKH)</sub>	Output setup time, BEx valid before SSCLK high	0.5P - 1.3	ns
4	toh(SSCLKH-BEIV)	Output hold time, BEx invalid after SSCLK high	*0.5P – 2.3	ns
5	t <sub>osu(EAV-SSCLKH)</sub>	Output setup time, EAx valid before SSCLK high	0.5P - 1.3	ns
6	toh(SSCLKH-EAIV)	Output hold time, EAx invalid after SSCLK high	*0.5P – 2.3	ns
9	tosu(ADSV-SSCLKH)	Output setup time, SSADS valid before SSCLK high	0.5P - 1.3	ns
10	toh(SSCLKH-ADSV)	Output hold time, SSADS valid after SSCLK high	0.5P - 2.3	ns
11	t <sub>osu(OEV-SSCLKH)</sub>	Output setup time, SSOE valid before SSCLK high	0.5P - 1.3	ns
12	toh(SSCLKH-OEV)	Output hold time, SSOE valid after SSCLK high	0.5P - 2.3	ns
13	t <sub>osu(EDV-SSCLKH)</sub>	Output setup time, EDx valid before SSCLK high	0.5P - 1.3	ns
14	toh(SSCLKH-EDIV)	Output hold time, EDx invalid after SSCLK high	*0.5P – 2.3	ns
15	t <sub>osu(WEV-SSCLKH)</sub>	Output setup time, SSWE valid before SSCLK high	0.5P - 1.3	ns
16	toh(SSCLKH-WEV)	Output hold time, SSWE valid after SSCLK high	0.5P - 2.3	ns

<sup>†</sup> When the PLL is used (CLKMODE x4), P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns. For CLKMODE x1, 0.5P is defined as PH (pulse duration of CLKIN high) for all output setup times; 0.5P is defined as PL (pulse duration of CLKIN low) for all output hold times.

<sup>\*</sup>Not production tested.

#### SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)

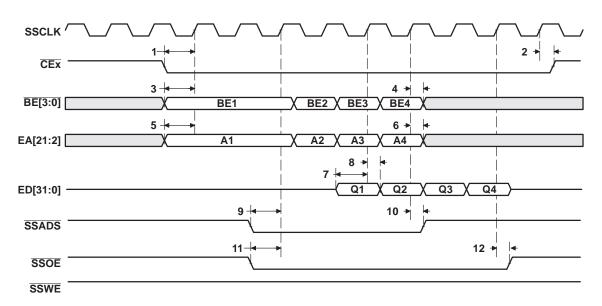


Figure 15. SBSRAM Read Timing (Full-Rate SSCLK)

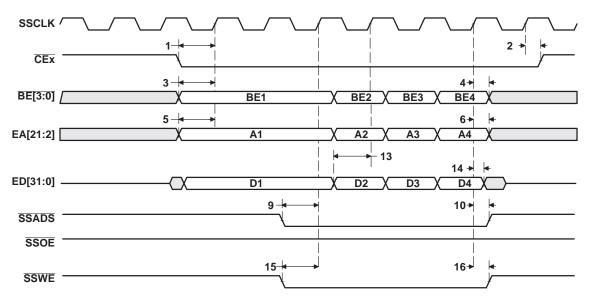


Figure 16. SBSRAM Write Timing (Full-Rate SSCLK)

#### SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)

# timing requirements for synchronous-burst SRAM cycles (half-rate SSCLK) (see Figure 17)

NO		'C6201B	LINUT
NO.		MIN MAX	UNIT
7	t <sub>su(EDV-SSCLKH)</sub> Setup time, read EDx valid before SSCLK high	2.5	ns
8	t <sub>h(SSCLKH-EDV)</sub> Hold time, read EDx valid after SSCLK high	1.5	ns

# switching characteristics for synchronous-burst SRAM cycles<sup>†</sup> (half-rate SSCLK) (see Figure 17 and Figure 18)

			'C6201B	
NO.		PARAMETER	MIN MAX	UNIT
1	tosu(CEV-SSCLKH)	Output setup time, CEx valid before SSCLK high	1.5P – 3	ns
2	toh(SSCLKH-CEV)	Output hold time, CEx valid after SSCLK high	0.5P - 1.5	ns
3	t <sub>osu(BEV-SSCLKH)</sub>	Output setup time, BEx valid before SSCLK high	1.5P – 3	ns
4	toh(SSCLKH-BEIV)	Output hold time, BEx invalid after SSCLK high	*0.5P – 1.5	ns
5	t <sub>osu(EAV-SSCLKH)</sub>	Output setup time, EAx valid before SSCLK high	1.5P – 3	ns
6	toh(SSCLKH-EAIV)	Output hold time, EAx invalid after SSCLK high	*0.5P – 1.5	ns
9	t <sub>osu(ADSV-SSCLKH)</sub>	Output setup time, SSADS valid before SSCLK high	1.5P – 3	ns
10	toh(SSCLKH-ADSV)	Output hold time, SSADS valid after SSCLK high	0.5P - 1.5	ns
11	t <sub>osu(OEV-SSCLKH)</sub>	Output setup time, SSOE valid before SSCLK high	1.5P – 3	ns
12	toh(SSCLKH-OEV)	Output hold time, SSOE valid after SSCLK high	0.5P - 1.5	ns
13	t <sub>osu(EDV-SSCLKH)</sub>	Output setup time, EDx valid before SSCLK high	1.5P – 3	ns
14	toh(SSCLKH-EDIV)	Output hold time, EDx invalid after SSCLK high	*0.5P – 1.5	ns
15	t <sub>osu(WEV-SSCLKH)</sub>	Output setup time, SSWE valid before SSCLK high	1.5P – 3	ns
16	t <sub>oh(SSCLKH-WEV)</sub>	Output hold time, SSWE valid after SSCLK high	0.5P - 1.5	ns

<sup>†</sup> When the PLL is used (CLKMODE x4), P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns. For CLKMODE x1:



<sup>1.5</sup>P = P + PH, where P = 1/CPU clock frequency, and PH = pulse duration of CLKIN high.

<sup>0.5</sup>P = PL, where PL = pulse duration of CLKIN low.

<sup>\*</sup>Not production tested.

#### SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)

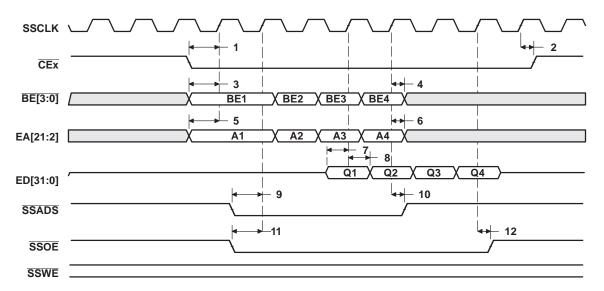


Figure 17. SBSRAM Read Timing (1/2 Rate SSCLK)

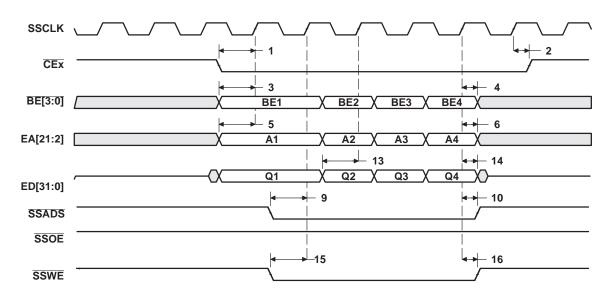


Figure 18. SBSRAM Write Timing (1/2 Rate SSCLK)

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#### SYNCHRONOUS DRAM TIMING

#### timing requirements for synchronous DRAM cycles (see Figure 19)

NO		'C6201B	
NO.		MIN MAX	UNIT
7	t <sub>su(EDV-SDCLKH)</sub> Setup time, read EDx valid before SDCLK high	0.5	ns
8	t <sub>h(SDCLKH-EDV)</sub> Hold time, read EDx valid after SDCLK high	3	ns

#### switching characteristics for synchronous DRAM cycles<sup>†</sup> (see Figure 19–Figure 24)

	2.2.44555		'C6201B	
NO.		PARAMETER	MIN MAX	UNIT
1	t <sub>osu(CEV-SDCLKH)</sub>	Output setup time, CEx valid before SDCLK high	1.5P – 3.5	ns
2	toh(SDCLKH-CEV)	Output hold time, CEx valid after SDCLK high	0.5P – 1	ns
3	t <sub>osu</sub> (BEV-SDCLKH)	Output setup time, BEx valid before SDCLK high	1.5P – 3.5	ns
4	toh(SDCLKH-BEIV)	Output hold time, BEx invalid after SDCLK high	*0.5P – 1	ns
5	t <sub>osu(EAV-SDCLKH)</sub>	Output setup time, EAx valid before SDCLK high	1.5P – 3.5	ns
6	toh(SDCLKH-EAIV)	Output hold time, EAx invalid after SDCLK high	*0.5P – 1	ns
9	t <sub>osu</sub> (SDCAS-SDCLKH)	Output setup time, SDCAS valid before SDCLK high	1.5P – 3.5	ns
10	toh(SDCLKH-SDCAS)	Output hold time, SDCAS valid after SDCLK high	0.5P - 1	ns
11	t <sub>osu(EDV-SDCLKH)</sub>	Output setup time, EDx valid before SDCLK high	1.5P – 3.5	ns
12	toh(SDCLKH-EDIV)	Output hold time, EDx invalid after SDCLK high	*0.5P – 1	ns
13	t <sub>osu</sub> (SDWE-SDCLKH)	Output setup time, SDWE valid before SDCLK high	1.5P = 3.5	ns
14	toh(SDCLKH-SDWE)	Output hold time, SDWE valid after SDCLK high	0.5P - 1	ns
15	t <sub>osu</sub> (SDA10V-SDCLKH)	Output setup time, SDA10 valid before SDCLK high	1.5P - 3.5	ns
16	toh(SDCLKH-SDA10IV)	Output hold time, SDA10 invalid after SDCLK high	*0.5P – 1	ns
17	t <sub>osu</sub> (SDRAS-SDCLKH)	Output setup time, SDRAS valid before SDCLK high	1.5P – 3.5	ns
18	toh(SDCLKH-SDRAS)	Output hold time, SDRAS valid after SDCLK high	0.5P – 1	ns

<sup>†</sup> When the PLL is used (CLKMODE x4), P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns. For CLKMODE x1.



<sup>1.5</sup>P = P + PH, where P = 1/CPU clock frequency, and PH = pulse duration of CLKIN high.

<sup>0.5</sup>P = PL, where PL = pulse duration of CLKIN low.

<sup>\*</sup>Not production tested.

#### **SYNCHRONOUS DRAM TIMING (CONTINUED)**

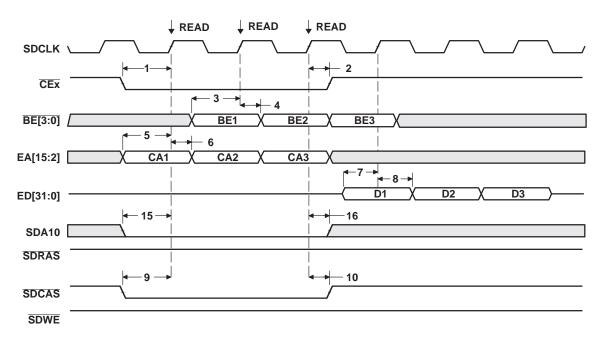


Figure 19. Three SDRAM Read Commands

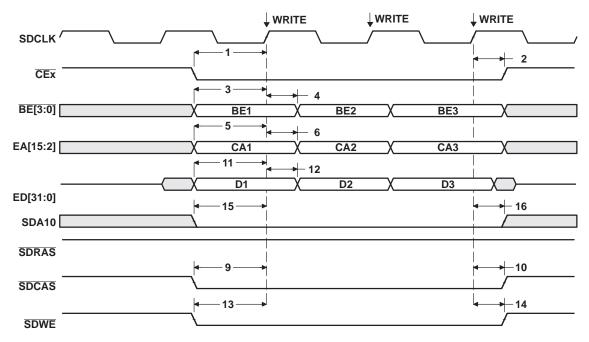


Figure 20. Three SDRAM WRT Commands

### **SYNCHRONOUS DRAM TIMING (CONTINUED)**

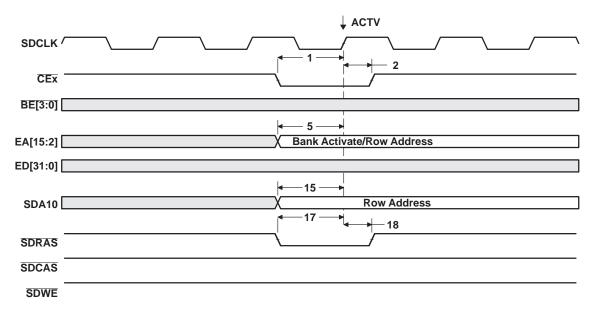


Figure 21. SDRAM ACTV Command

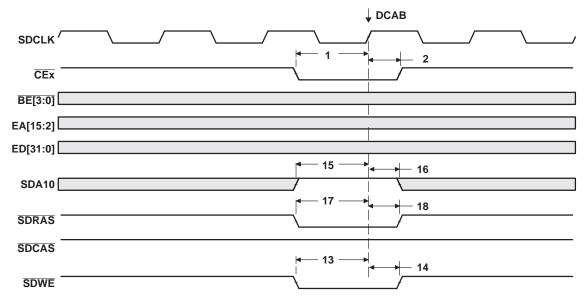


Figure 22. SDRAM DCAB Command

### **SYNCHRONOUS DRAM TIMING (CONTINUED)**

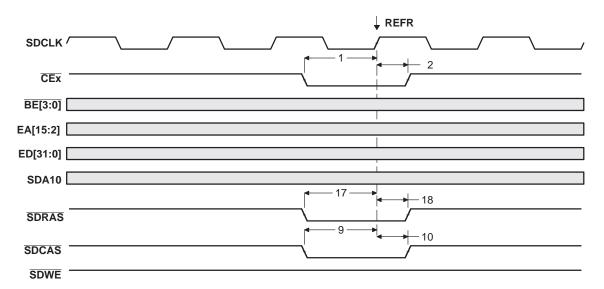


Figure 23. SDRAM REFR Command

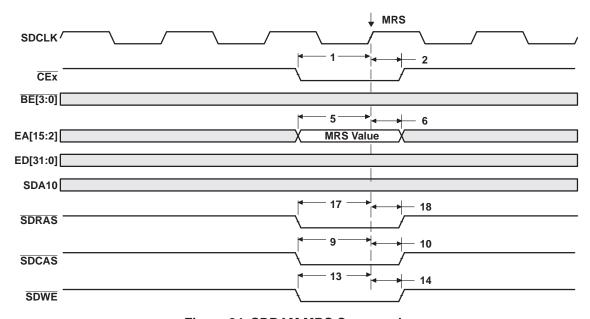


Figure 24. SDRAM MRS Command

#### **HOLD/HOLDA TIMING**

#### timing requirements for the HOLD/HOLDA cycles<sup>†</sup> (see Figure 25)

No			'C6201B		
NO.			MIN	MAX	UNIT
1	t <sub>su(HOLDH-CKO1H)</sub>	Setup time, HOLD high before CLKOUT1 high	*1		ns
2	t <sub>h(CKO1H-HOLDL)</sub>	Hold time, HOLD low after CLKOUT1 high	*4		ns

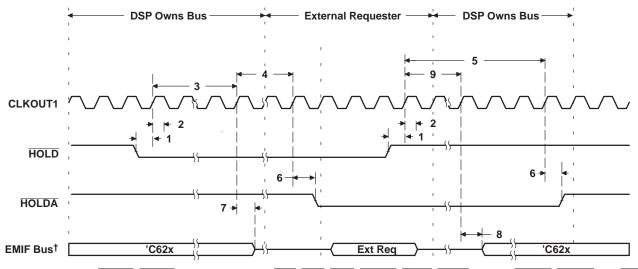
<sup>†</sup> HOLD is synchronized internally. Therefore, if setup and hold times are not met, it will either be recognized in the current cycle or in the next cycle. Thus, HOLD can be an asynchronous input.

#### switching characteristics for the HOLD/HOLDA cycles<sup>‡</sup> (see Figure 25)

		'C62			
NO.	PARAMETER		MIN	MAX	UNIT
3	t <sub>R(HOLDL-BHZ)</sub>	Response time, HOLD low to EMIF Bus high impedance	*4P	§	ns
4	t <sub>R(BHZ-HOLDAL)</sub>	Response time, EMIF Bus high impedance to HOLDA low	*P	*2P	ns
5	t <sub>R</sub> (HOLDH-HOLDAH)	Response time, HOLD high to HOLDA high	*4P	*7P	ns
6	t <sub>d</sub> (CKO1H-HOLDAL)	Delay time, CLKOUT1 high to HOLDA valid	*1	8	ns
7	t <sub>d(CKO1H-BHZ)</sub>	Delay time, CLKOUT1 high to EMIF Bus high impedance¶	*3	*11	ns
8	t <sub>d(CKO1H-BLZ)</sub>	Delay time, CLKOUT1 high to EMIF Bus low impedance¶	*3	*11	ns
9	t <sub>R(HOLDH-BLZ)</sub>	Response time, HOLD high to EMIF Bus low impedance	*3P	*6P	ns

<sup>&</sup>lt;sup>‡</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>¶</sup> EMIF Bus consists of CE[3:0], BE[3:0], ED[31:0], EA[21:2], ARE, AOE, AWE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, and SDWE.



<sup>†</sup> EMIF Bus consists of CE[3:0], BE[3:0], ED[31:0], EA[21:2], ARE, AOE, AWE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, and SDWE.

Figure 25. HOLD/HOLDA Timing



<sup>\*</sup>Not production tested.

<sup>\*</sup>Not production tested.

<sup>§</sup> All pending EMIF transactions are allowed to complete before HOLDA is asserted. The worst cases for this is an asynchronous read or write with external ARDY used or a minimum of eight consecutive SDRAM reads or writes when RBTR8 = 1. If no bus transactions are occurring, then the minimum delay time can be achieved. Also, bus hold can be indefinitely delayed by setting NOHOLD = 1.

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#### **RESET TIMING**

#### timing requirements for reset (see Figure 26)

NO			'C6201B		LINUT
NO.			MIN	MAX	UNIT
1	t <sub>w(RST)</sub>	Width of the RESET pulse (PLL stable) <sup>†</sup>	*10		CLKOUT1 cycles
		Width of the RESET pulse (PLL needs to sync up) <sup>‡</sup>	250		μs

<sup>†</sup> This parameter applies to CLKMODE x1 when CLKIN is stable and applies to CLKMODE x4 when CLKIN and PLL are stable.

#### switching characteristics during reset§¶ (see Figure 26)

NO.			'C6201B			
	PARAMETER				MAX	UNIT
2	t <sub>R(RST)</sub>	Response time to change of value in RESET signal		2		CLKOUT1 cycles
3	t <sub>d</sub> (CKO1H-CKO2IV)	Delay time, CLKOUT1 high to CLKOUT2 invalid		*-1		ns
4	t <sub>d</sub> (CKO1H-CKO2V)	Delay time, CLKOUT1 high to CLKOUT2 valid			10	ns
5	t <sub>d</sub> (CKO1H-SDCLKIV)	Delay time, CLKOUT1 high to SDCLK invalid		*-1		ns
6	t <sub>d</sub> (CKO1H-SDCLKV)	Delay time, CLKOUT1 high to SDCLK valid			10	ns
7	t <sub>d</sub> (CKO1H-SSCKIV)	Delay time, CLKOUT1 high to SSCLK invalid		*-1		ns
8	t <sub>d</sub> (CKO1H-SSCKV)	Delay time, CLKOUT1 high to SSCLK valid			10	ns
9	t <sub>d</sub> (CKO1H-LOWIV)	Delay time, CLKOUT1 high to low group invalid		*-1		ns
10	t <sub>d</sub> (CKO1H-LOWV)	Delay time, CLKOUT1 high to low group valid			*10	ns
11	t <sub>d</sub> (CKO1H-HIGHIV)	Delay time, CLKOUT1 high to high group invalid		*-1		ns
12	t <sub>d</sub> (CKO1H-HIGHV)	Delay time, CLKOUT1 high to high group valid			*10	ns
13	t <sub>d(CKO1H-ZHZ)</sub>	Delay time, CLKOUT1 high to Z group high impedance		*-1		ns
14	t <sub>d(CKO1H-ZV)</sub>	Delay time, CLKOUT1 high to Z group valid			*10	ns

<sup>§</sup> Low group consists of: IACK, INUM[3:0], DMAC[3:0], PD, TOUT0, and TOUT1 High group consists of: HINT

Z group consists of: EA[21:2], ED[31:0], CE[3:0], BE[3:0], ARE, AWE, AOE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, SDWE, HD[15:0], CLKX0, CLKX1, FSX0, FSX1, DX0, DX1, CLKR0, CLKR1, FSR0, and FSR1.



<sup>&</sup>lt;sup>‡</sup> This parameter only applies to CLKMODE x4. The RESET signal is not connected internally to the clock PLL circuit. The PLL, however, may need up to 250 µs to stabilize following device power up or after PLL configuration has been changed. During that time, RESET must be asserted to ensure proper device operation. See the *clock PLL* section for PLL lock times.

<sup>\*</sup>Not production tested.

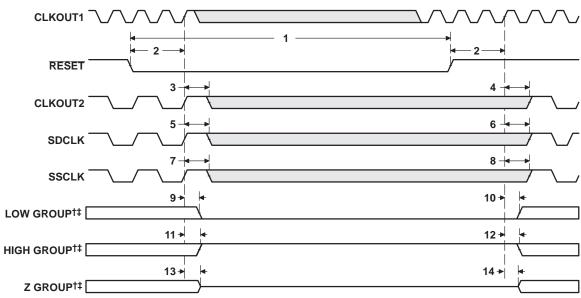
<sup>¶</sup> HRDY is gated by input HCS.

If  $\overline{HCS} = 0$  at device reset,  $\overline{HRDY}$  belongs to the high group.

If HCS = 1 at device reset, HRDY belongs to the low group.

<sup>\*</sup>Not production tested.

#### **RESET TIMING (CONTINUED)**



<sup>†</sup> Low group consists of: IACK, INUM[3:0], DMAC[3:0], PD, TOUT0, and TOUT1

High group consists of: HIN

Z group consists of: EA[21:2], ED[31:0],  $\overline{\text{CE}[3:0]}$ ,  $\overline{\text{BE}[3:0]}$ ,  $\overline{\text{ARE}}$ ,  $\overline{\text{AWE}}$ ,  $\overline{\text{AOE}}$ ,  $\overline{\text{SSOE}}$ ,  $\overline{\text{SSWE}}$ ,  $\overline{\text{SDAIO}}$ ,  $\overline{\text{SDRAS}}$ ,  $\overline{\text{SDCAS}}$ ,

SDWE, HD[15:0], CLKX0, CLKX1, FSX0, FSX1, DX0, DX1, CLKR0, CLKR1, FSR0, and FSR1.

‡ HRDY is gated by input HCS.

If  $\overline{HCS} = 0$  at device reset,  $\overline{HRDY}$  belongs to the high group. If  $\overline{HCS} = 1$  at device reset,  $\overline{HRDY}$  belongs to the low group.

Figure 26. Reset Timing

#### **EXTERNAL INTERRUPT TIMING**

### timing requirements for interrupt response cycles<sup>†‡</sup> (see Figure 27)

NO	NO		'C6201B		
NO.		MIN	MAX	UNIT	
2	t <sub>w(ILOW)</sub> Width of the interrupt pulse low	*2P		ns	
3	t <sub>w(IHIGH)</sub> Width of the interrupt pulse high	*2P		ns	

<sup>†</sup> Interrupt signals are synchronized internally and are potentially recognized one cycle later if setup and hold times are violated. Thus, they can be connected to asynchronous inputs.

# switching characteristics during interrupt response cycles§ (see Figure 27)

NO	PARAMETER		'C620		
NO.			MIN	MAX	UNIT
1	t <sub>R(EINTH-IACKH)</sub>	Response time, EXT_INTx high to IACK high	*9P		ns
4	t <sub>d(CKO2L-IACKV)</sub> [	Delay time, CLKOUT2 low to IACK valid	*-4	6	ns
5	t <sub>d(CKO2L-INUMV)</sub> [	Delay time, CLKOUT2 low to INUMx valid		6	ns
6	t <sub>d(CKO2L-INUMIV)</sub> [	Delay time, CLKOUT2 low to INUMx invalid	*-4		ns

 $<sup>\</sup>$  P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns. When the PLL is used (CLKMODE x4), 0.5P = 1/(2 × CPU clock frequency). For CLKMODE x1: 0.5P = PH, where PH is the high period of CLKIN.

<sup>\*</sup>Not production tested.

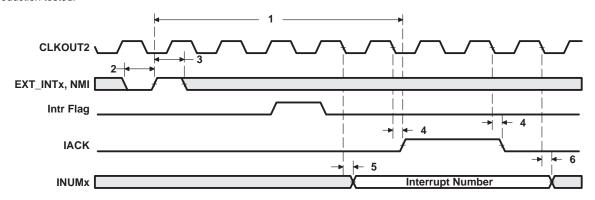


Figure 27. Interrupt Timing

 $<sup>^{\</sup>ddagger}$  P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>\*</sup>Not production tested.

#### HOST-PORT INTERFACE TIMING

# timing requirements for host-port interface cycles<sup>†‡</sup> (see Figure 28, Figure 29, Figure 30, and Figure 31)

			'C6201B		
NO.			MIN	IIN MAX	UNIT
1	t <sub>su(SEL-HSTBL)</sub>	Setup time, select signals§ valid before HSTROBE low	4		ns
2	t <sub>h(HSTBL-SEL)</sub>	Hold time, select signals§ valid after HSTROBE low	2		ns
3	t <sub>w(HSTBL)</sub>	Pulse duration, HSTROBE low	2P		ns
4	t <sub>w(HSTBH)</sub>	Pulse duration, HSTROBE high between consecutive accesses	*2P		ns
10	t <sub>su(SEL-HASL)</sub>	Setup time, select signals§ valid before HAS low	4		ns
11	t <sub>h(HASL-SEL)</sub>	Hold time, select signals§ valid after HAS low	2		ns
12	t <sub>su(HDV-HSTBH)</sub>	Setup time, host data valid before HSTROBE high	4		ns
13	t <sub>h(HSTBH-HDV)</sub>	Hold time, host data valid after HSTROBE high	2		ns
14	t <sub>h(HRDYL-HSTBL)</sub>	Hold time, HSTROBE low after HRDY low. HSTROBE shoul not be inactivated until HRDY is active (low); otherwise, HPI writes will not complete properly.	*1		ns
18	t <sub>su(HASL-HSTBL)</sub>	Setup time, HAS low before HSTROBE low	*2		ns
19	t <sub>h(HSTBL-HASL)</sub>	Hold time, HAS low after HSTROBE low	*2		ns

<sup>†</sup> HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

# switching characteristics during host-port interface cycles<sup>†‡</sup> (see Figure 28, Figure 29, Figure 30, and Figure 31)

	PARAMETER.		'C62		
NO.		PARAMETER	MIN	MAX	UNIT
5	t <sub>d(HCS-HRDY)</sub>	Delay time, HCS to HRDY¶	*1	9	ns
6	t <sub>d(HSTBL-HRDYH)</sub>	Delay time, HSTROBE low to HRDY high#	*3	12	ns
7	toh(HSTBL-HDLZ)	Output hold time, HD low impedance after HSTROBE low for an HPI read	*4		ns
8	t <sub>d</sub> (HDV-HRDYL)	Delay time, HD valid to HRDY low	*P-3	*P + 3	ns
9	t <sub>oh(HSTBH-HDV)</sub>	Output hold time, HD valid after HSTROBE high	*1	*12	ns
15	t <sub>d(HSTBH-HDHZ)</sub>	Delay time, HSTROBE high to HD high impedance	*3	*12	ns
16	t <sub>d</sub> (HSTBL-HDV)	Delay time, HSTROBE low to HD valid	*2	*12	ns
17	t <sub>d</sub> (HSTBH-HRDYH)	Delay time, HSTROBE high to HRDY high	*3	12	ns

 $<sup>\</sup>dagger$  HSTROBE refers to the following logical operation on  $\overline{HCS}$ ,  $\overline{HDS1}$ , and  $\overline{HDS2}$ : [NOT( $\overline{HDS1}$  XOR  $\overline{HDS2}$ )] OR  $\overline{HCS}$ .



<sup>&</sup>lt;sup>‡</sup> The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>§</sup> Select signals include: HCNTRL[1:0], HR/W, and HHWIL.

<sup>\*</sup>Not production tested.

<sup>&</sup>lt;sup>‡</sup> The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

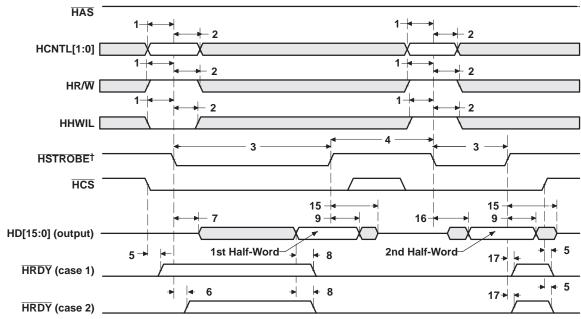
<sup>¶</sup> HCS enables HRDY, and HRDY is always low when HCS is high. The case where HRDY goes high when HCS falls indicates that HPI is busy completing a previous HPID write or READ with autoincrement.

<sup>#</sup> This parameter is used during an HPID read. At the beginning of the first half-word transfer on the falling edge of HSTROBE, the HPI sends the request to the DMA auxiliary channel, and HRDY remains high until the DMA auxiliary channel loads the requested data into HPID.

This parameter is used after the second half-word of an HPID write or autoincrement read. HRDY remains low if the access is not an HPID write or autoincrement read. Reading or writing to HPIC or HPIA does not affect the HRDY signal.

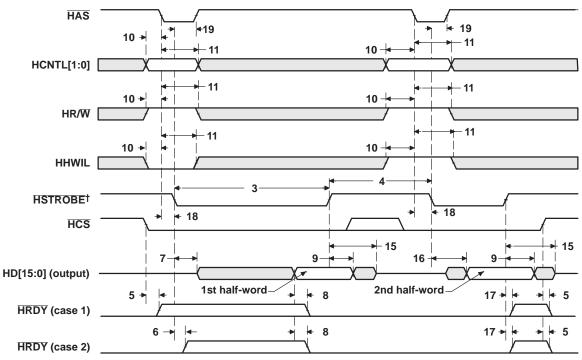
<sup>\*</sup>Not production tested.

#### **HOST-PORT INTERFACE TIMING (CONTINUED)**



 $<sup>^{\</sup>dagger}$   $\overline{\text{HSTROBE}}$  refers to the following logical operation on  $\overline{\text{HCS}}$ ,  $\overline{\text{HDS1}}$ , and  $\overline{\text{HDS2}}$ : [NOT( $\overline{\text{HDS1}}$  XOR  $\overline{\text{HDS2}}$ )] OR  $\overline{\text{HCS}}$ .

Figure 28. HPI Read Timing (HAS Not Used, Tied High)

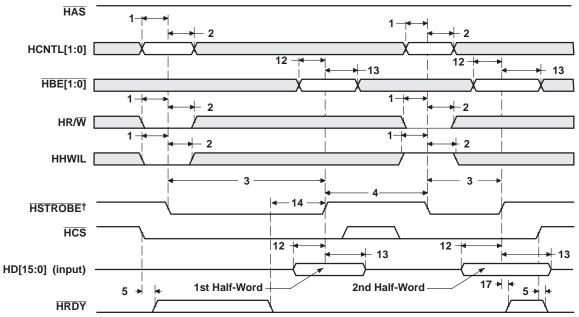


<sup>†</sup> HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

Figure 29. HPI Read Timing (HAS Used)

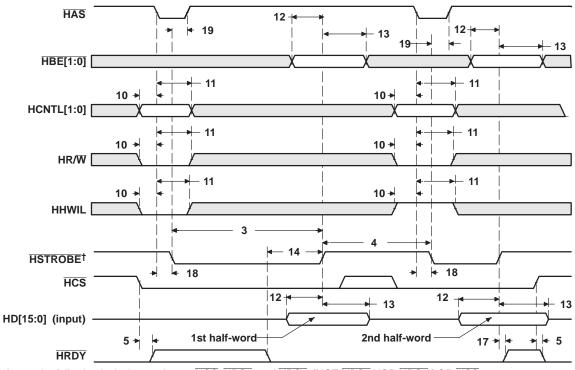


#### **HOST-PORT INTERFACE TIMING (CONTINUED)**



 $<sup>^{\</sup>dagger}$   $\overline{\text{HSTROBE}}$  refers to the following logical operation on  $\overline{\text{HCS}}$ ,  $\overline{\text{HDS1}}$ , and  $\overline{\text{HDS2}}$ : [NOT( $\overline{\text{HDS1}}$  XOR  $\overline{\text{HDS2}}$ )] OR  $\overline{\text{HCS}}$ .

Figure 30. HPI Write Timing (HAS Not Used, Tied High)



 $<sup>^{\</sup>dagger}$   $\overline{\text{HSTROBE}}$  refers to the following logical operation on  $\overline{\text{HCS}}$ ,  $\overline{\text{HDS1}}$ , and  $\overline{\text{HDS2}}$ : [NOT( $\overline{\text{HDS1}}$  XOR  $\overline{\text{HDS2}}$ )] OR  $\overline{\text{HCS}}$ .

Figure 31. HPI Write Timing (HAS Used)y



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#### **MULTICHANNEL BUFFERED SERIAL PORT TIMING**

## timing requirements for McBSP<sup>†‡</sup>(see Figure 32)

				'C62	01B	
NO.				MIN	MAX	UNIT
2	t <sub>c(CKRX)</sub>	Cycle time, CLKR/X	CLKR/X ext	*2P		ns
3	t <sub>w(CKRX)</sub>	Pulse duration, CLKR/X high or CLKR/X low	CLKR/X ext	*P – 1		ns
_		Saturatima, autornal ESB high hafara CLKB law	CLKR int	*9		
5	t <sub>su</sub> (FRH-CKRL)	Setup time, external FSR high before CLKR low	CLKR ext	2		ns
6	t <sub>h(CKRL-FRH)</sub>	KRL-FRH) Hold time, external FSR high after CLKR low	CLKR int	*6		
6			CLKR ext	3		ns
7		Cation times DD valid haters CLIVD lave	CLKR int	8		
7	t <sub>su(DRV-CKRL)</sub>	Setup time, DR valid before CLKR low	CLKR ext	1		ns
	4	Hold fire a DD valid often CLVD lave	CLKR int	3		
8	th(CKRL-DRV)	Hold time, DR valid after CLKR low	CLKR ext	4		ns
40		Oction times automated FOV high before OLKY law.	CLKX int	9		
10	t <sub>su</sub> (FXH-CKXL)	Setup time, external FSX high before CLKX low	CLKX ext	2	·	ns
44		Lield time automal FOV high after CLIVV law.	CLKX int	6	·	
11	th(CKXL-FXH)	Hold time, external FSX high after CLKX low	CLKX ext	3	·	ns

<sup>†</sup> CLKRP = CLKXP = FSRP = FSXP = 0. If polarity of any of the signals is inverted, then the timing references of that signal are also inverted.

 $<sup>^\</sup>ddagger$  P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>\*</sup>Not production tested

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#### MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

## switching characteristics for McBSP<sup>†‡§</sup> (see Figure 32)

NO			'C620	)1B	LINUT	
NO.		PARAMETER		MIN	MAX	UNIT
1	t <sub>d</sub> (CKSH-CKRXH)	Delay time, CLKS high to CLKR/X high for internal CLKR/X generated from CLKS input		3	10	ns
2	t <sub>c(CKRX)</sub>	Cycle time, CLKR/X	CLKR/X int	2P		ns
3	t <sub>w(CKRX)</sub>	Pulse duration, CLKR/X high or CLKR/X low	CLKR/X int	*C - 1.6¶	*C + 1¶	ns
4	t <sub>d(CKRH-FRV)</sub>	Delay time, CLKR high to internal FSR valid	CLKR int	*-2.5	3	ns
		D. I. C. OHOVILLA I. J. IEOV. II.	CLKX int	*-2	3	
9	t <sub>d</sub> (CKXH-FXV)	Delay time, CLKX high to internal FSX valid	CLKX ext	*3	*9	ns
40		Disable time, DX high impedance following last data bit from	CLKX int	*-1	*4	
12	<sup>t</sup> dis(CKXH-DXHZ)	CLKX high	CLKX ext	*3	*9	ns
40		Delegation OLIV Entrop DV wellst	CLKX int	*-1	*4	
13	t <sub>d</sub> (CKXH-DXV)	Delay time, CLKX high to DX valid	CLKX ext	*3	*9	ns
		Delay time, FSX high to DX valid	FSX int	*-1	*3	
14	<sup>t</sup> d(FXH-DXV)	ONLY applies when in data delay 0 (XDATDLY = 00b) mode	FSX ext	*3	*9	ns

<sup>†</sup> CLKRP = CLKXP = FSRP = FSXP = 0. If polarity of any of the signals is inverted, then the timing references of that signal are also inverted.

S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

= sample rate generator input clock = P\_clks if CLKSM = 0 (P\_clks = CLKS period)

H = CLKX high pulse width = (CLKGDV/2 + 1) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

<sup>&</sup>lt;sup>‡</sup> Minimum delay times also represent minimum output hold times.

 $<sup>\</sup>$  P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

<sup>\*</sup>Not production tested.

 $<sup>^{\</sup>P}C = HorL$ 

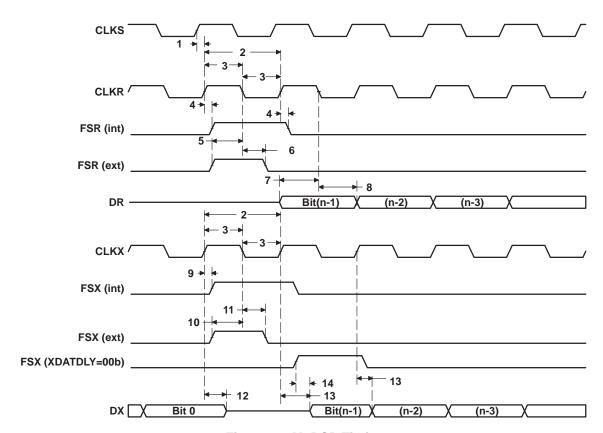


Figure 32. McBSP Timings

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#### MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

#### timing requirements for FSR when GSYNC = 1 (see Figure 33)

NO			'C620	'C6201B	
NO.			MIN	MAX	UNIT
1	t <sub>su(FRH-CKSH)</sub>	Setup time, FSR high before CLKS high	4		ns
2	t <sub>h(CKSH-FRH)</sub>	Hold time, FSR high after CLKS high	4		ns

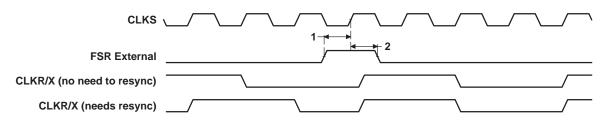


Figure 33. FSR Timing When GSYNC = 1

## timing requirements for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = $0^{\dagger \ddagger}$ (see Figure 34)

				'C62	201B		
NO.			MAST	ER	SLA\	/E	UNIT
			MIN	MAX	MIN	MAX	
4	t <sub>su(DRV-CKXL)</sub>	Setup time, DR valid before CLKX low	12		2 – 3P		ns
5	t <sub>h(CKXL-DRV)</sub>	Hold time, DR valid after CLKX low	4		5 + 6P		ns

 $<sup>^{\</sup>dagger}$  P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

# switching characteristics for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = $0^{\dagger \ddagger}$ (see Figure 34)

					'C6201B						
NO.		PARAMETER		MASTER§		AVE	UNIT				
			MIN	MAX	MIN	MAX					
1	t <sub>h(CKXL-FXL)</sub>	Hold time, FSX low after CLKX low¶	T-2	*T + 3			ns				
2	t <sub>d(FXL-CKXH)</sub>	Delay time, FSX low to CLKX high#	*L – 2	L+3			ns				
3	t <sub>d</sub> (CKXH-DXV)	Delay time, CLKX high to DX valid	*-2	4	*3P + 4	5P + 17	ns				
6	t <sub>dis(CKXL-DXHZ)</sub>	Disable time, DX high impedance following last data bit from CLKX low	*L-2	*L + 3			ns				
7	t <sub>dis(FXH-DXHZ)</sub>	Disable time, DX high impedance following last data bit from FSX high			*P + 3	*3P + 17	ns				
8	t <sub>d(FXL-DXV)</sub>	Delay time, FSX low to DX valid			*2P + 2	4P + 17	ns				

<sup>†</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

H = CLKX high pulse width = (CLKGDV/2 + 1) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

<sup>#</sup> FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).

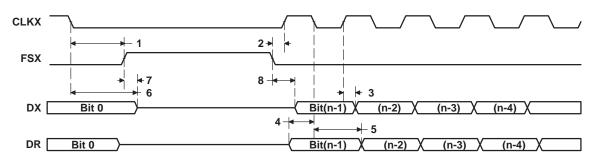


Figure 34. McBSP Timing as SPI Master or Slave: CLKSTP = 10b, CLKXP = 0

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP



<sup>&</sup>lt;sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

<sup>§</sup> S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

<sup>=</sup> sample rate generator input clock = P\_clks if CLKSM = 0 (P\_clks = CLKS period)

T = CLKX period = (1 + CLKGDV) \* S

FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

<sup>\*</sup>Not production tested.

<sup>¶</sup> FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

<sup>#</sup> FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).

#### timing requirements for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = $0^{\dagger \ddagger}$ (see Figure 35)

						'C6201B				
NO.			MAS	TER	SLA	٧E	UNIT			
			MIN	MAX	MIN	MAX				
4	t <sub>su(DRV-CKXH)</sub>	Setup time, DR valid before CLKX high	12		2 – 3P		ns			
5	t <sub>h(CKXH-DRV)</sub>	Hold time, DR valid after CLKX high	4		5 + 6P		ns			

 $<sup>^{\</sup>dagger}$  P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

# switching characteristics for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = $0^{\dagger \ddagger}$ (see Figure 35)

				'C6201B					
NO.		PARAMETER	MAST	ER§	SL	AVE	UNIT		
			MIN	MAX	MIN	MAX			
1	t <sub>h(CKXL-FXL)</sub>	Hold time, FSX low after CLKX low¶	L – 2	*L + 3			ns		
2	t <sub>d(FXL-CKXH)</sub>	Delay time, FSX low to CLKX high#	*T – 2	T + 3			ns		
3	t <sub>d(CKXL-DXV)</sub>	Delay time, CLKX low to DX valid	*-2	4	*3P + 4	5P + 17	ns		
6	t <sub>dis</sub> (CKXL-DXHZ)	Disable time, DX high impedance following last data bit from CLKX low	*-2	*4	*3P + 3	*5P + 17	ns		
7	t <sub>d(FXL-DXV)</sub>	Delay time, FSX low to DX valid	*H – 2	H + 4	*2P + 2	4P + 17	ns		

 $<sup>^{\</sup>dagger}$  P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

H = CLKX high pulse width = (CLKGDV/2 + 1) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

<sup>#</sup> FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).

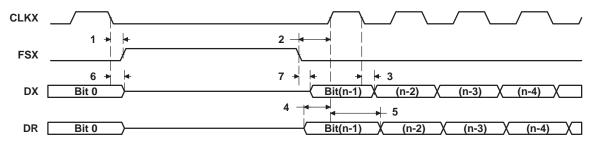


Figure 35. McBSP Timing as SPI Master or Slave: CLKSTP = 11b, CLKXP = 0



For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

<sup>&</sup>lt;sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

<sup>§</sup> S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

<sup>=</sup> sample rate generator input clock = P\_clks if CLKSM = 0 (P\_clks = CLKS period)

T = CLKX period = (1 + CLKGDV) \* S

FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

<sup>\*</sup>Not production tested.

### timing requirements for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 1<sup>†‡</sup> (see Figure 36)

						'C6201B				
NO.			MAS	TER	SLA	٧E	UNIT			
			MIN	MAX	MIN	MAX				
4	t <sub>su(DRV-CKXH)</sub>	Setup time, DR valid before CLKX high	12		2 – 3P		ns			
5	t <sub>h(CKXH-DRV)</sub>	Hold time, DR valid after CLKX high	4		5 + 6P		ns			

 $<sup>^{\</sup>dagger}$  P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

# switching characteristics for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = $1^{\dagger \ddagger}$ (see Figure 36)

				'C6201B					
NO.	PARAMETER		MASTER§		SLAVE		UNIT		
			MIN	MAX	MIN	MAX			
1	t <sub>h(CKXH-FXL)</sub>	Hold time, FSX low after CLKX high¶	T – 2	*T + 3			ns		
2	t <sub>d</sub> (FXL-CKXL)	Delay time, FSX low to CLKX low#	*H – 2	H + 3			ns		
3	t <sub>d(CKXL-DXV)</sub>	Delay time, CLKX low to DX valid	*-2	4	*3P + 4	5P + 17	ns		
6	t <sub>dis</sub> (CKXH-DXHZ)	Disable time, DX high impedance following last data bit from CLKX high	*H – 2	*H + 3			ns		
7	t <sub>dis</sub> (FXH-DXHZ)	Disable time, DX high impedance following last data bit from FSX high			*P + 3	*3P + 17	ns		
8	t <sub>d(FXL-DXV)</sub>	Delay time, FSX low to DX valid		•	*2P + 2	4P + 17	ns		

<sup>†</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

T = CLKX period = (1 + CLKGDV) \* S

H = CLKX high pulse width = (CLKGDV/2 + 1) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

<sup>#</sup> FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).

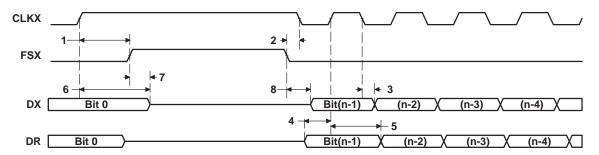


Figure 36. McBSP Timing as SPI Master or Slave: CLKSTP = 10b, CLKXP = 1



For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

<sup>&</sup>lt;sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

<sup>§</sup> S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

<sup>=</sup> sample rate generator input clock = P\_clks if CLKSM = 0 (P\_clks = CLKS period)

<sup>¶</sup> FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

<sup>\*</sup>Not production tested.

#### timing requirements for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 1<sup>†‡</sup> (see Figure 37)

						'C6201B				
NO.			MAS	TER	SLA	٧E	UNIT			
			MIN	MAX	MIN	MAX				
4	t <sub>su(DRV-CKXL)</sub>	Setup time, DR valid before CLKX low	12		2 – 3P		ns			
5	t <sub>h(CKXL-DRV)</sub>	Hold time, DR valid after CLKX low	4		5 + 6P		ns			

 $<sup>^\</sup>dagger$  P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

#### switching characteristics for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 1<sup>†‡</sup> (see Figure 37)

		PARAMETER		'C6201B					
NO.				ER§	SLA	UNIT			
			MIN	MAX	MIN	MAX			
1	t <sub>h(CKXH-FXL)</sub>	Hold time, FSX low after CLKX high <sup>¶</sup>	H – 2	*H + 3			ns		
2	t <sub>d(FXL-CKXL)</sub>	Delay time, FSX low to CLKX low#	*T – 2	T + 1			ns		
3	t <sub>d(CKXH-DXV)</sub>	Delay time, CLKX high to DX valid	*-2	4	*3P + 3	5P + 17	ns		
6	t <sub>dis(CKXH-DXHZ)</sub>	Disable time, DX high impedance following last data bit from CLKX high	*–2	*4	*3P + 3	*5P + 17	ns		
7	t <sub>d(FXL-DXV)</sub>	Delay time, FSX low to DX valid	*L – 2	L + 4	*2P + 2	4P + 17	ns		

<sup>&</sup>lt;sup>†</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

H = CLKX high pulse width = (CLKGDV/2 + 1) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) \* S if CLKGDV is even

= (CLKGDV + 1)/2 \* S if CLKGDV is odd or zero

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).

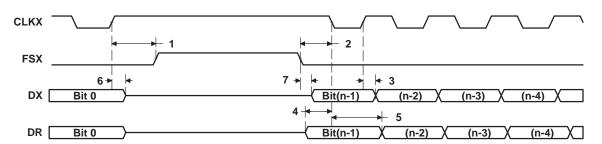


Figure 37. McBSP Timing as SPI Master or Slave: CLKSTP = 11b, CLKXP = 1



<sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

<sup>&</sup>lt;sup>‡</sup> For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

<sup>§</sup> S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

sample rate generator input clock = P\_clks if CLKSM = 0 (P\_clks = CLKS period)

T = CLKX period = (1 + CLKGDV) \* S

<sup>¶</sup> FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

<sup>\*</sup>Not production tested.

#### DMAC, TIMER, POWER-DOWN TIMING

#### switching characteristics for DMAC outputs (see Figure 38)

NO	DADAMETED	'C62	LINUT	
NO.	PARAMETER	MIN	MAX	UNIT
1	t <sub>d(CKO1H-DMACV)</sub> Delay time, CLKOUT1 high to DMAC valid	*2	10	ns

<sup>\*</sup>Not production tested.

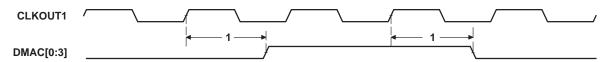


Figure 38. DMAC Timing

#### timing requirements for timer inputs<sup>†</sup> (see Figure 39)

NO			'C6201B	
NO.		MIN	MAX	UNIT
1	t <sub>w(TINP)</sub> Pulse duration, TINP high or low	*2P		ns

<sup>†</sup> P = 1/CPU clock frequency in ns. For example, when running parts at 200 MHz, use P = 5 ns.

#### switching characteristics for timer outputs (see Figure 39)

		'C6201B		
NO.	PARAMETER	MIN MAX	UNIT	
2	t <sub>d(CKO1H-TOUTV)</sub> Delay time, CLKOUT1 high to TOUT valid	*2	9	ns

<sup>\*</sup>Not production tested.

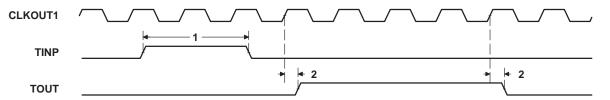


Figure 39. Timer Timing

#### switching characteristics for power-down outputs (see Figure 40)

NO	PARAMETER	'C6201B		LINUT
NO.		MIN	MAX	UNIT
1	t <sub>d(CKO1H-PDV)</sub> Delay time, CLKOUT1 high to PD valid	*2	9	ns

<sup>\*</sup>Not production tested.



Figure 40. Power-Down Timing



<sup>\*</sup>Not production tested.

#### **JTAG TEST-PORT TIMING**

## timing requirements for JTAG test port (see Figure 41)

NO			'C6201B		
NO.			MIN	MAX	UNIT
1	t <sub>c(TCK)</sub>	Cycle time, TCK	*50		ns
3	t <sub>su(TDIV-TCKH)</sub>	Setup time, TDI/TMS/TRST valid before TCK high	*10		ns
4	t <sub>h(TCKH-TDIV)</sub>	Hold time, TDI/TMS/TRST valid after TCK high	*5		ns

<sup>\*</sup>Not production tested.

#### switching characteristics for JTAG test port (see Figure 41)

 NO	PARAMETER	'C6201B		
NO.		MIN	MAX	UNIT
2	t <sub>d(TCKL-TDOV)</sub> Delay time, TCK low to TDO valid	*0	*15	ns

<sup>\*</sup>Not production tested.

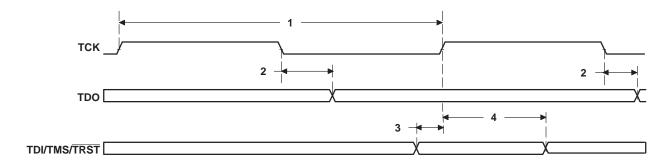
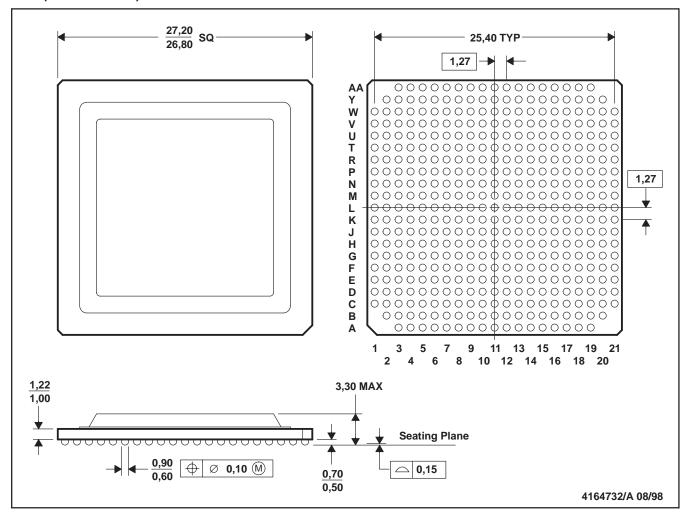


Figure 41. JTAG Test-Port Timing

#### **MECHANICAL DATA**

#### GLP (S-CBGA-N429)

#### **CERAMIC BALL GRID ARRAY**



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-156
- D. Flip chip application only
- E. For 320C6201B (1.8 V core device).
- F. Package weight for GLP is 7.65 grams.

#### thermal resistance characteristics (S-CBGA package)

NO			°C/W	Air Flow
1	RΘ <sub>JC</sub>	Junction-to-Case, measured to the bottom of solder ball	3.0	N/A
2	$R\Theta_{JC}$	Junction-to-Case, measured to the top of the package lid	7.3	N/A
3	RΘJA	Junction-to-Ambient	14.5	0
4	RΘ <sub>JMA</sub>	Junction-to-Moving-Air	11.8	150 fpm
5			11.1	250 fpm
6			10.2	500 fpm
7	RΘ <sub>JB</sub>	Junction-to-Board, measured by soldering a thermocouple to one of the middle traces on the board at the edge of the package	6.2	N/A



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